

RL78/L1A

R01DS0280EJ0100

Rev. 1.00

Aug 12, 2016

Integrated LCD controller/driver, 12-bit resolution A/D Converter, 12-bit resolution D/A Converter, Operational amplifier, Internal reference voltage for A/D and D/A converters. True Low Power Platform (as low as 70.8 μ A/MHz, and 0.68 μ A in Halt mode(RTC2 + LVD)), 1.8 V to 3.6 V operation, 48 to 128 Kbyte Flash, 33 DMIPS at 24 MHz, for All LCD Based Applications.

1. OUTLINE

1.1 Features

Ultra-low power consumption technology

- V_{DD} = single power supply voltage of 1.8 to 3.6 V
- HALT mode
- STOP mode
- SNOOZE mode

RL78 CPU core

- CISC architecture with 3-stage pipeline
- Minimum instruction execution time: Can be changed from high speed (0.04167 μ s: @ 24 MHz operation with high-speed on-chip oscillator clock) to ultra-low speed (30.5 μ s: @ 32.768 kHz operation with subsystem clock)
- Multiply/divide and multiply/accumulate instructions are supported.
- Address space: 1 MB
- General-purpose registers: (8-bit register \times 8) \times 4 banks
- On-chip RAM: 5.5 KB

Code flash memory

- Code flash memory: 48 to 128 KB
- Block size: 1 KB
- Prohibition of block erase and rewriting (security function)
- On-chip debug function
- Self-programming (with boot swap function/flash shield window function)

Data flash memory

- Data flash memory: 8 KB
- Background operation (BGO): Instructions can be executed from the program memory while rewriting the data flash memory.
- Number of rewrites: 1,000,000 times (TYP.)
- Voltage of rewrites: V_{DD} = 1.8 to 3.6 V

High-speed on-chip oscillator

- Select from 24 MHz, 16 MHz, 12 MHz, 8 MHz, 6 MHz, 4 MHz, 3 MHz, 2 MHz, and 1 MHz
- High accuracy: $\pm 1.0\%$ ($V_{DD} = 1.8$ to 3.6 V, $T_A = -20$ to $+85^\circ\text{C}$)

Operating ambient temperature

- $T_A = -40$ to $+85^\circ\text{C}$ (A: Consumer applications)

Power management and reset function

- On-chip power-on-reset (POR) circuit
- On-chip voltage detector (LVD) (Select interrupt and reset from 10 levels)

Data transfer controller (DTC)

- Transfer modes: Normal transfer mode, repeat transfer mode, block transfer mode
- Activation sources: Activated by interrupt sources (30 sources).
- Chain transfer function

Event link controller (ELC)

- Event signals of 22 types can be linked to the specified peripheral function.

Serial interfaces

- | | |
|---|------------|
| • CSI/CSI (SPI supported): | 4 channels |
| • UART: | 4 channels |
| • I ² C/simplified I ² C: | 5 channels |

Timers

- 16-bit timer: 8 channels
- 8-bit timer: 2 channels
- 12-bit interval timer: 1 channel
- Real-time clock 2: 1 channel (calendar for 99 years, alarm function, and clock correction function)
- Watchdog timer: 1 channel (operable with the dedicated low-speed on-chip oscillator)

LCD controller/driver

- Internal voltage boosting method, capacitor split method, and external resistance division method are switchable.
- Segment signal output: 32 (28) to 45 (41) Note 1
- Common signal output: 4 (8) Note 1

A/D converter

- 12-bit resolution A/D converter (1.8 V \leq $AV_{DD} \leq V_{DD} \leq$ 3.6 V)
- Analog input: 10 to 14 channels
- Internal reference voltage (TYP. 1.45 V) and temperature sensor Note 2

D/A converter

- 12-bit resolution D/A converter (1.8 V \leq $AV_{DD} \leq V_{DD} \leq$ 3.6 V)
- Analog output: 2 channels
- Output voltage: 0.35 V to $AV_{DD} - 0.47$ V

Voltage reference

- The output voltage can be selected from among 1.5 V (typ.), 1.8 V (typ.), 2.048 V (typ.), and 2.5 V (typ.).
- Can be used as the internal reference voltage for A/D and D/A converters.

Comparator

- 1 channel
- Operating modes: Comparator high-speed mode, comparator low-speed mode, window mode
- The external reference voltage or internal reference voltage can be selected as the reference voltage.

Operational amplifier

- General-purpose operational amplifier: 1 channel
- Rail-to-rail operational amplifier with analog MUX: 2 channels

I/O ports

- I/O ports: 59 to 79 (N-ch open drain I/O [withstand voltage of 6 V]: 2)
- Can be set to N-ch open drain, TTL input buffer, and on-chip pull-up resistor
- On-chip key interrupt function
- On-chip clock output/buzzer output controller

Others

- On-chip BCD (binary-coded decimal) correction circuit

Note 1. The number in parentheses indicates the number of signal outputs when 8 coms are used.

Note 2. Selectable only in HS (high-speed main) mode.

Note 3. The functions mounted depend on the product.
See 1.6 Outline of Functions.

- ROM, RAM capacities

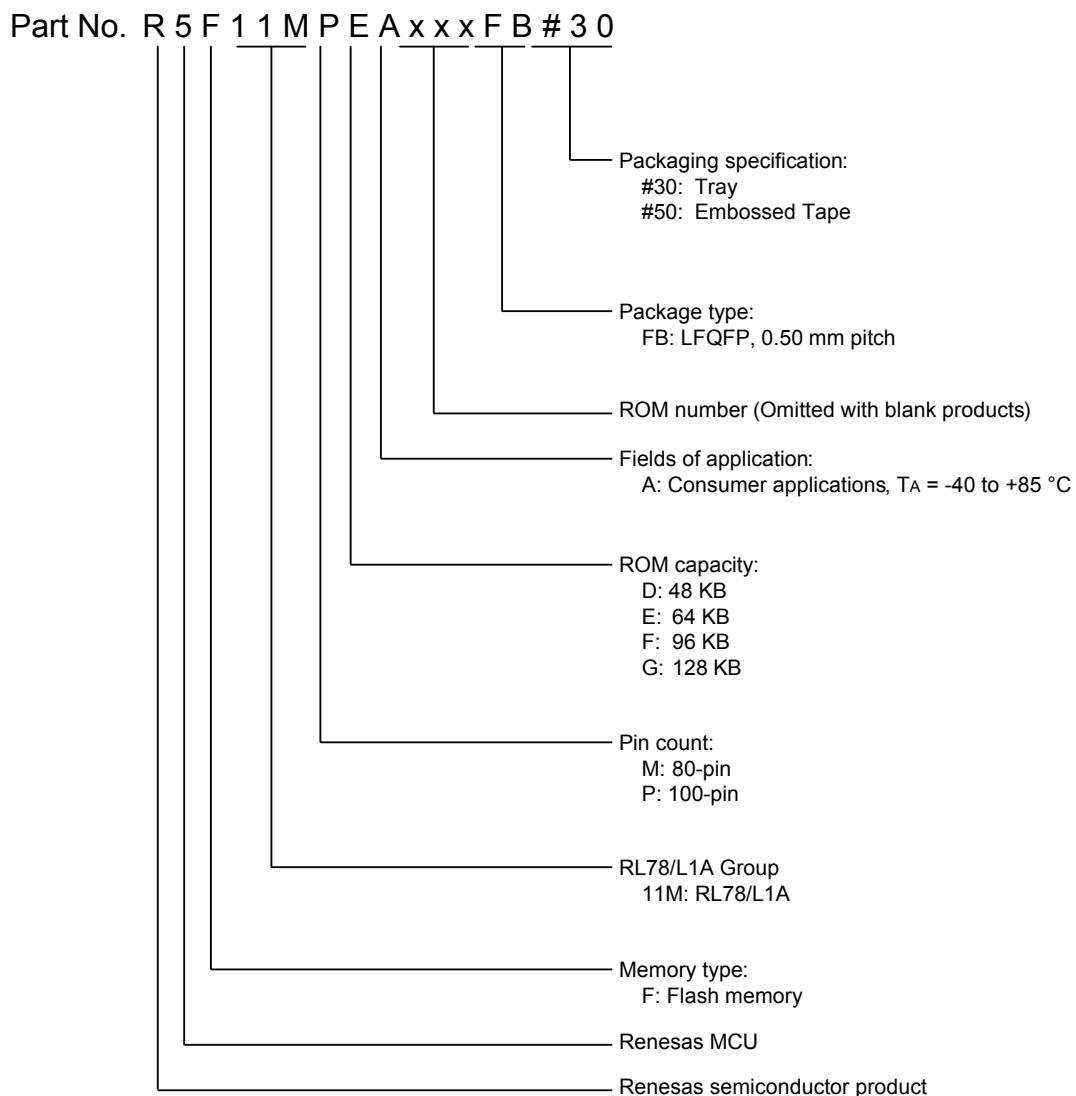
Products with USB

Flash ROM	Data Flash	RAM	RL78/L1A	
			80 pins	100 pins
128 KB	8 KB	5.5 KB	—	R5F11MPG
96 KB	8 KB	5.5 KB	R5F11MMF	R5F11MPF
64 KB	8 KB	5.5 KB	R5F11MME	R5F11MPE
48 KB	8 KB	5.5 KB	R5F11MMD	—

1.2 Ordering Information

Pin Count	Package	Fields of Application	Orderable Part Number
80 pins	80-pin plastic LFQFP (12 × 12 mm, 0.5 mm pitch)	A	R5F11MMDAFB#30, R5F11MMEA#30, R5F11MFAFB#30 R5F11MMDAFB#50, R5F11MMEA#50, R5F11MMFAFB#50
100 pins	100-pin plastic LFQFP (14 × 14 mm, 0.5 mm pitch)	A	R5F11MPEAFB#30, R5F11MPFAFB#30, R5F11MPGAFB#30 R5F11MPEAFB#50, R5F11MPFAFB#50, R5F11MPGAFB#50

Figure 1 - 1 Part Number, Memory Size, and Package of RL78/L1A



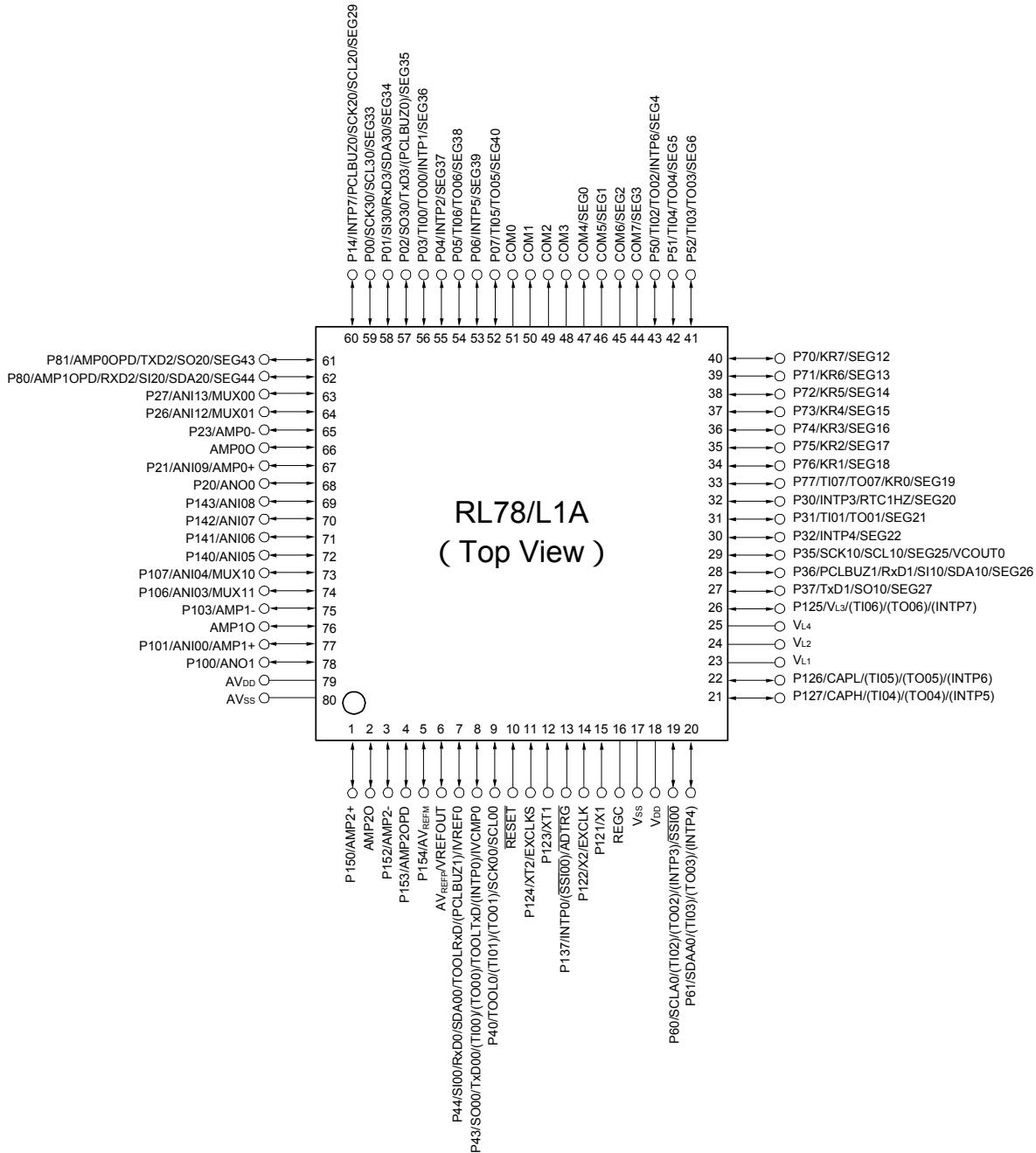
Caution Orderable part numbers are current as of when this manual was published.

Please make sure to refer to the relevant product page on the Renesas website for the latest part numbers.

1.3 Pin Configuration (Top View)

1.3.1 80-pin products

- 80-pin plastic LFQFP (fine pitch) (12' 12 mm, 0.5 mm pitch)



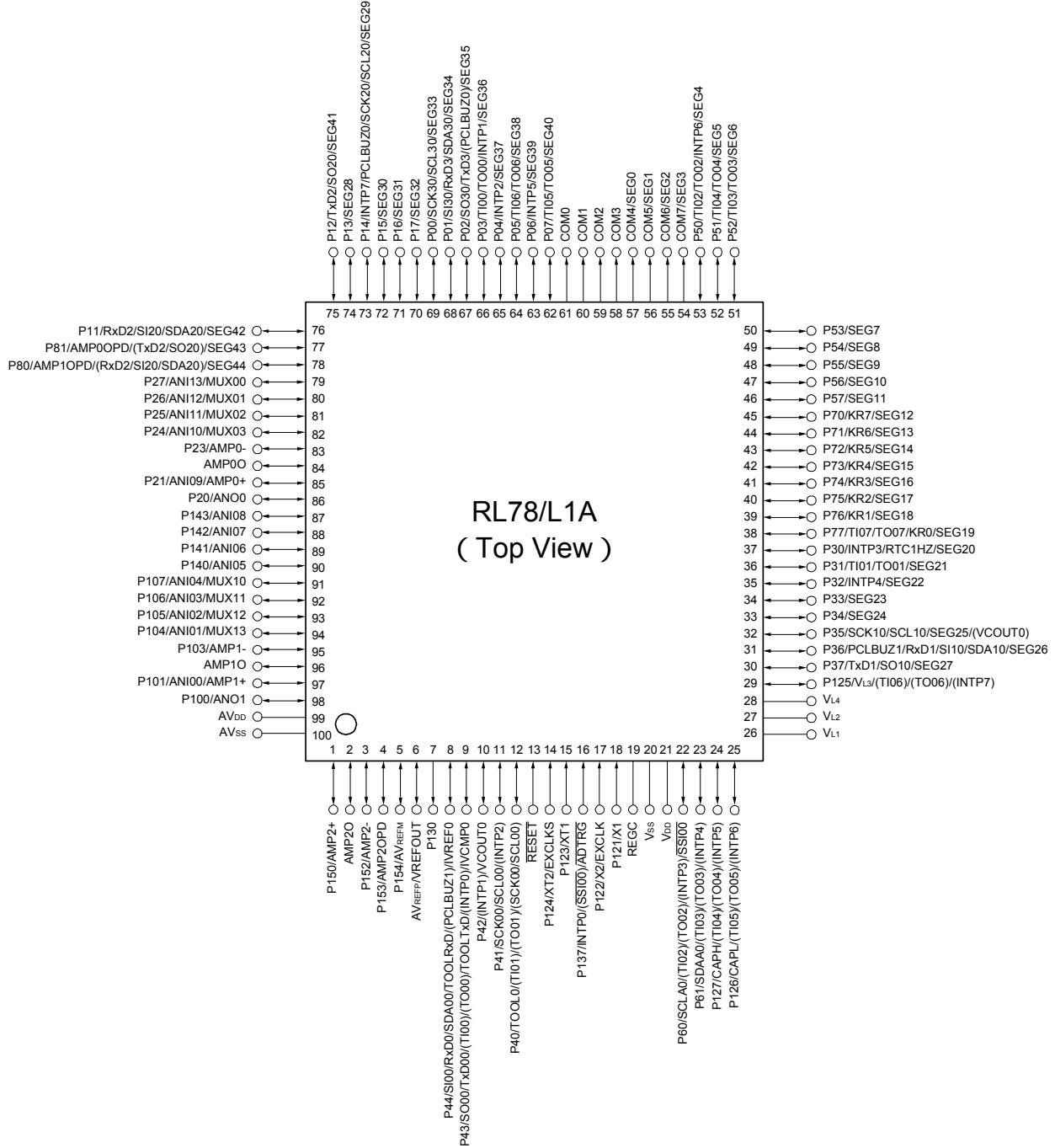
Caution Connect the REGC pin to VSS pin via a capacitor (0.47 to 1 μ F).

Remark 1. For pin identification, see 1.4 Pin Identification.

Remark 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.3.2 100-pin products

- 100-pin plastic LFQFP (fine pitch) (14×14 mm, 0.5 mm pitch)



Caution Connect the REGC pin to V_S pin via a capacitor (0.47 to 1 μ F).

Remark 1. For pin identification, see **1.4 Pin Identification**.

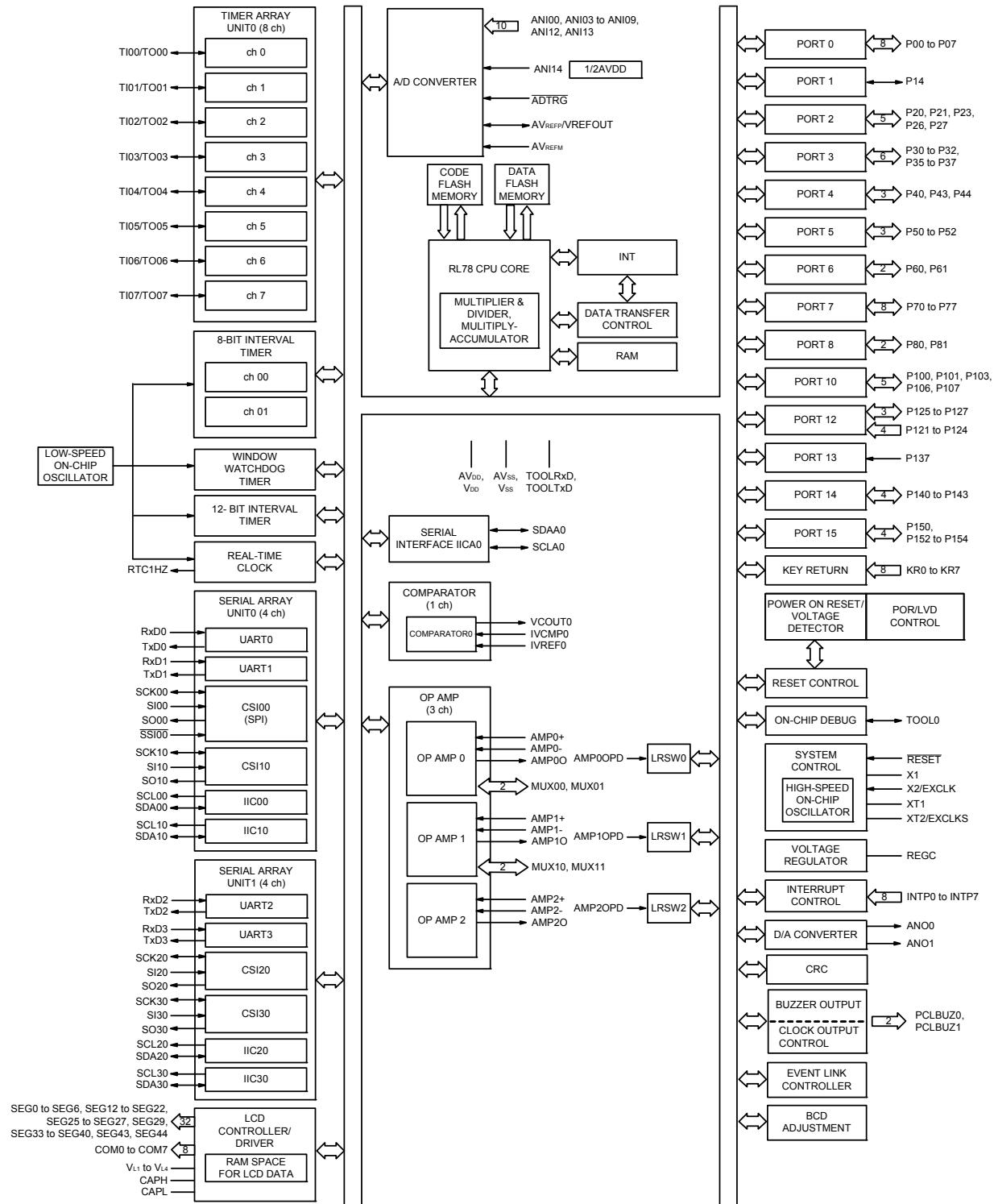
Remark 2. Functions in parentheses in the above figure can be assigned via settings in the peripheral I/O redirection register (PIOR).

1.4 Pin Identification

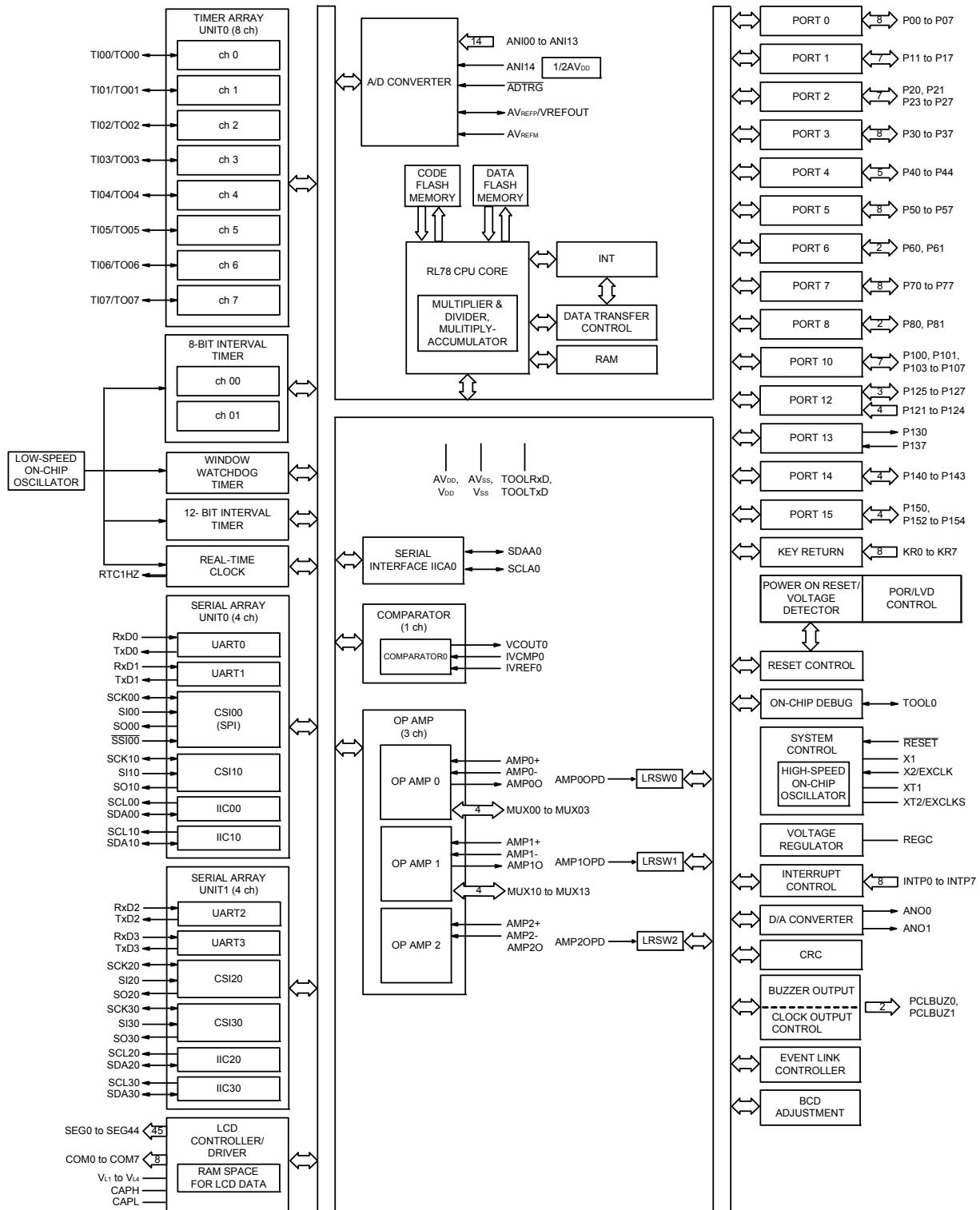
AMP0+ to AMP2+	: OP AMP + Input	PCLBUZ0, PCLBUZ1	: Programmable Clock Output/ Buzzer Output
AMP0- to AMP2+	: OP AMP - Input	REGC	: Regulator Capacitance
AMP0O to AMP2+	: OP AMP Output	<u>RESET</u>	: Reset
AMP0OPD to AMP2OPD	: Low Resistance Switch	RTC1HZ	: Real-time Clock Correction
<u>ADTRG</u>	: A/D External Trigger Input	RxD0 to RxD3	: Receive Data
AN10 to ANI14	: Analog Input	SCK00, SCK10, SCK20,	: Serial Clock Input/Output
ANO0, ANO1	: Analog Output	SCK30	
AVDD	: Analog Power Supply	SCLA0	: Serial Clock Input/Output
AVREFM	: Analog Reference Voltage	SCL00, SCL10, SCL20, SCL30	: Serial Clock Output
	Minus	SDAA0, SDA00, SDA10,	: Serial Data Input/Output
AVREFP	: Analog Reference Voltage	SDA20, SDA30	
	Plus	SEG0 to SEG55	: LCD Segment Output
AVss	: Analog Ground	SI00, SI10, SI20, SI30	: Serial Data Input
CAPH, CAPL	: Capacitor for LCD	SO00, SO10, SO20, SO30	: Serial Data Output
COM0 to COM7	: LCD Common Output	<u>SSI00</u>	: Slave Select Input
EXCLK	: External Clock Input (Main System Clock)	TI00 to TI07	: Timer Input
EXCLKS	: External Clock Input (Sub System Clock)	TO00 to TO07	: Timer Output
INTP0 to INTP7	: External Interrupt Input	TOOL0	: Data Input/Output for Tool
IVCMP0	: Comparator Input	TOOLRxD, TOOLTxD	: Data Input/Output for External Device
IVREF0	: Comparator Reference Input	TxD0 to TxD3	: Transmit Data
KR0 to KR7	: Key Return	VCOUT0	: Comparator Output
MUX00 to MUX03,	: OP AMP output analog MUX	V _{DD}	: Power Supply
MUX10 to MUX13	switch	V _{L1} to V _{L4}	: LCD Power Supply
P00 to P07	: Port 0	VREFOUT	: Analog Reference Voltage
P11 to P17	: Port 1	V _{ss}	: Output
P20, P21 P23 to P27	: Port 2	X1, X2	: Ground
P30 to P37	: Port 3		: Crystal Oscillator
P40 to P44	: Port 4	XT1, XT2	: (Main System Clock)
P50 to P57	: Port 5		: Crystal Oscillator
P60, P61	: Port 6		: (Subsystem Clock)
P70 to P77	: Port 7		
P80, P81	: Port 8		
P100, P101	: Port 10		
P103 to P107			
P121 to P127	: Port 12		
P130, P137	: Port 13		
P140 to P143	: Port 14		
P150, P152 to P154	: Port 15		

1.5 Block Diagram

1.5.1 80-pin products



1.5.2 100-pin products



1.6 Outline of Functions

[80-pin, 100-pin products]

(1/2)

Item	80-pin	100-pin	
	R5F11MMx (x = D to F)	R5F11MPx (x = E to G)	
Code flash memory (KB)	48 to 96	64 to 128	
Data flash memory (KB)	8	8	
RAM (KB)	5.5	5.5	
Memory space	1 MB		
Main system clock	High-speed system clock X1 (crystal/ceramic) oscillation, external main system clock input (EXCLK) 1 to 20 MHz: V _{DD} = 2.7 to 3.6 V, 1 to 8 MHz: V _{DD} = 1.8 to 2.7 V		
	High-speed on-chip oscillator clock HS (high-speed main) operation mode: 1 to 24 MHz (V _{DD} = 2.7 to 3.6 V), HS (high-speed main) operation mode: 1 to 16 MHz (V _{DD} = 2.4 to 3.6 V), LS (low-speed main) operation mode: 1 to 8 MHz (V _{DD} = 1.8 to 3.6 V)		
Subsystem clock	XT1 (crystal) oscillation, external subsystem clock input (EXCLKS) 32.768 kHz (TYP.): V _{DD} = 1.8 to 3.6 V		
Low-speed on-chip oscillator clock	15 kHz (TYP.): V _{DD} = 1.8 to 3.6 V		
General-purpose register	8 bits × 32 registers (8 bits × 8 registers × 4 banks)		
Minimum instruction execution time	0.04167 µs (High-speed on-chip oscillator clock: f _{HOCO} = f _{HS} = 24 MHz operation) 0.05 µs (High-speed system clock: f _{MX} = 20 MHz operation) 30.5 µs (Subsystem clock: f _{SUB} = 32.768 kHz operation)		
Instruction set	<ul style="list-style-type: none"> • Data transfer (8/16 bits) • Adder and subtractor/logical operation (8/16 bits) • Multiplication (8 bits × 8 bits, 16 bits × 16 bits), Division (16 bits ÷ 16 bits, 32 bits ÷ 32 bits) • Multiplication and Accumulation (16 bits × 16 bits + 32 bits) • Rotate, barrel shift, and bit manipulation (Set, reset, test, and Boolean operation), etc. 		
I/O port	Total CMOS I/O CMOS input CMOS output N-ch open-drain I/O (6 V tolerance)	59 52 5 0 2	79 71 5 1 2
Timer	16-bit timer TAU 8-bit or 16-bit interval timer Watchdog timer 12-bit interval timer Real-time clock 2 RTC output	8 channels (Timer outputs: 8, PWM outputs: 7 Note) 2 channels (8 bits) / 1 channel (16 bits) 1 channel 1 channel 1 channel 1 Hz (subsystem clock: f _{SUB} = 32.768 kHz)	

Note The number of outputs varies, depending on the setting of channels in use and the number of the master.

(2/2)

Item	80-pin	100-pin
	R5F11MMx (x = D to F)	R5F11MPx (x = E to G)
Clock output/buzzer output	2	2
	<ul style="list-style-type: none"> • 2.44 kHz, 4.88 kHz, 9.76 kHz, 1.25 MHz, 2.5 MHz, 5 MHz, 10 MHz (Main system clock: f_{MAIN} = 20 MHz operation) • 256 Hz, 512 Hz, 1.024 kHz, 2.048 kHz, 4.096 kHz, 8.192 kHz, 16.384 kHz, 32.768 kHz (Subsystem clock: f_{sub} = 32.768 kHz operation) 	
12-bit resolution A/D converter	10 channels	14 channels
12-bit resolution D/A converter	2 channels	2 channels
VREFOUT (voltage reference)	2.5 V/2.048 V/1.8 V/1.5 V	
Operational amplifier	3 channels	3 channels
AMPnO with analog MUX switch	2 channels (2 in-out/channel)	2 channels (4 in-out/channel)
Comparator	1 channel	1 channel
Serial interface	<ul style="list-style-type: none"> • CSI (SPI supported): 1 channel/UART (LIN-bus supported): 1 channel/simplified I²C: 1 channel • CSI: 1 channel/UART: 1 channel/simplified I²C: 1 channel • CSI: 1 channel/UART: 1 channel/simplified I²C: 1 channel • CSI: 1 channel/UART: 1 channel/simplified I²C: 1 channel 	
I ² C bus	1 channel	1 channel
LCD controller/driver	Internal voltage boosting method, capacitor split method, and external resistance division method are switchable.	
Segment signal output	32 (28) Note 1	45 (41) Note 1
Common signal output	4 (8) Note 1	
Data transfer controller (DTC)	30 sources	30 sources
Event link controller (ELC)	Event input: 22, Event trigger output: 8	Event input: 22, Event trigger output: 8
Vectored interrupt sources	Internal	31
	External	9
Key interrupt	8	8
Reset	<ul style="list-style-type: none"> • Reset by RESET pin • Internal reset by watchdog timer • Internal reset by power-on-reset • Internal reset by voltage detector • Internal reset by illegal instruction execution Note 2 • Internal reset by RAM parity error • Internal reset by illegal-memory access 	
Power-on-reset circuit	<ul style="list-style-type: none"> • Power-on-reset: 1.51 ±0.04 V • Power-down-reset: 1.50 ±0.04 V 	
Voltage detector	<ul style="list-style-type: none"> • Rising edge: 1.88 V to 3.13 V (10 stages) • Falling edge: 1.84 V to 3.06 V (10 stages) 	
On-chip debug function	Provided	
Power supply voltage	V _D D = 1.8 to 3.6 V	
Operating ambient temperature	T _A = -40 to +85 °C (A: Consumer applications)	

Note 1. The number in parentheses indicates the number of signal outputs when 8 coms are used.

Note 2. The illegal instruction is generated when instruction code FFH is executed.

Reset by the illegal instruction execution not is issued by emulation with the in-circuit emulator or on-chip debug emulator.

2. ELECTRICAL SPECIFICATIONS (A: TA = -40 to +85 °C)

This chapter describes the electrical specifications for the products A: Consumer applications (TA = -40 to +85 °C).

Caution 1. The RL78 microcontroller has an on-chip debug function, which is provided for development and evaluation. Do not use the on-chip debug function in products designated for mass production, because the guaranteed number of rewritable times of the flash memory may be exceeded when this function is used, and product reliability therefore cannot be guaranteed. Renesas Electronics is not liable for problems occurring when the on-chip debug function is used.

Caution 2. The pins mounted depend on the product. Refer to 2.1 Port Function to 2.2.1 With functions for each product in the RL78/L1A User's Manual.

2.1 Absolute Maximum Ratings

Absolute Maximum Ratings (TA = 25°C) (1/3)

Parameter	Symbols	Conditions	Ratings	Unit
Supply voltage	V _{DD}		-0.5 to +6.5	V
	AV _{DD}	AV _{DD} ≤ V _{DD}	-0.5 to +4.6	V
REGC pin input voltage	V _{IREGC}	REGC	-0.3 to +2.8 and -0.3 to V _{DD} + 0.3 Note 1	V
Input voltage	V _{I1}	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P137, EXCLK, EXCLKS, RESET	-0.3 to V _{DD} + 0.3 Note 2	V
	V _{I2}	P60, P61 (N-ch open-drain)	-0.3 to +6.5	V
	V _{I4}	IVCMP0	-0.7 to V _{DD} + 0.7	V
	V _{I5}	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	-0.3 to AV _{DD} + 0.3 Note 3	V
Output voltage	V _{O1}	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P60, P61, P70 to P77, P80, P81, P125 to P127, P130	-0.3 to V _{DD} + 0.3 Note 2	V
	V _{O2}	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	-0.3 to AV _{DD} + 0.3 Note 3	V
Analog input voltage	V _{AI1}	ANI0 to ANI13	-0.3 to AV _{DD} + 0.3 and AV _{REF(+)} + 0.3 Notes 2, 4	V

Note 1. Connect the REGC pin to Vss via a capacitor (0.47 to 1 µF). This value regulates the absolute maximum rating of the REGC pin. Do not use this pin with voltage applied to it.

Note 2. Must be 6.5 V or lower.

Note 3. Must be 4.6 V or lower.

Note 4. Do not exceed AV_{REF(+)} + 0.3 V in case of A/D conversion target pin.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark 1. Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

Remark 2. AV_{REF (+)}: + side reference voltage of the A/D converter.

Remark 3. V_{SS}: Reference voltage

Absolute Maximum Ratings (TA = 25°C)

(2/3)

Parameter	Symbols	Conditions	Ratings	Unit
LCD voltage	VL1	VL1 input voltage Note 1	-0.3 to +2.8	V
	VL2	VL2 input voltage Note 1	-0.3 to +6.5	V
	VL3	VL3 input voltage Note 1	-0.3 to +6.5	V
	VL4	VL4 input voltage Note 1	-0.3 to +6.5	V
	VL5	CAPL, CAPH input voltage Note 1	-0.3 to +6.5	V
	VLO1	VL1 output voltage	-0.3 to +2.8	V
	VLO2	VL2 output voltage	-0.3 to +6.5	V
	VLO3	VL3 output voltage	-0.3 to +6.5	V
	VLO4	VL4 output voltage	-0.3 to +6.5	V
	VLO5	CAPL, CAPH output voltage	-0.3 to +6.5	V
VLO6	COM0 to COM7 SEG0 to SEG44 output voltage	External resistance division method	-0.3 to VDD + 0.3 Note 2	V
		Capacitor split method	-0.3 to VDD + 0.3 Note 2	V
		Internal voltage boosting method	-0.3 to VL14 + 0.3 Note 2	V

Note 1. This value only indicates the absolute maximum ratings when applying voltage to the VL1, VL2, VL3, and VL4 pins; it does not mean that applying voltage to these pins is recommended. When using the internal voltage boosting method or capacitance split method, connect these pins to Vss via a capacitor (0.47 ± 30%) and connect a capacitor (0.47 ± 30%) between the CAPL and CAPH pins.

Note 2. Must be 6.5 V or lower.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Absolute Maximum Ratings (TA = 25°C)

(3/3)

Parameter	Symbols	Conditions		Ratings	Unit
Output current, high	IOH1	Per pin		-40	mA
		Total of all pins -170 mA	P40 to P44 P00 to P07, P11 to P17, P30 to P37, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130	-70 -100	mA mA
	IOH2	Per pin	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	-0.1	mA
		Total of all pins		-1.6 Note	mA
Output current, low	IOL1	Per pin		40	mA
		Total of all pins 170 mA	P40 to P44 P00 to P07, P11 to P17, P30 to P37, P50 to P57, P60, P61, P70 to P77, P80, P81, P125 to P127, P130	70 100	mA mA
	IOL2	Per pin	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	0.4	mA
		Total of all pins		6.4 Note	mA
Operating ambient temperature	TA	In normal operation mode		-40 to +85	°C
		In flash memory programming mode			
Storage temperature	Tstg			-65 to +150	°C

Note Do not exceed the rated values when outputting the current simultaneously 16 pins at maximum.

Caution Product quality may suffer if the absolute maximum rating is exceeded even momentarily for any parameter. That is, the absolute maximum ratings are rated values at which the product is on the verge of suffering physical damage, and therefore the product must be used under conditions that ensure that the absolute maximum ratings are not exceeded.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2.2 Oscillator Characteristics

2.2.1 X1 and XT1 oscillator characteristics

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Resonator	Conditions	MIN.	TYP.	MAX.	Unit
X1 clock oscillation frequency (fx) Note	Ceramic resonator/crystal resonator	2.7 V ≤ V _{DD} ≤ 3.6 V	1.0		20.0	MHz
		2.4 V ≤ V _{DD} < 2.7 V	1.0		16.0	
		1.8 V ≤ V _{DD} < 2.4 V	1.0		8.0	
XT1 clock oscillation frequency (fx _T) Note	Crystal resonator		32	32.768	35	kHz

Note Indicates only permissible oscillator frequency ranges. Refer to **AC Characteristics** for instruction execution time.
Request evaluation by the manufacturer of the oscillator circuit mounted on a board to check the oscillator characteristics.

Caution Since the CPU is started by the high-speed on-chip oscillator clock after a reset release, check the X1 clock oscillation stabilization time using the oscillation stabilization time counter status register (OSTC) by the user. Determine the oscillation stabilization time of the OSTC register and the oscillation stabilization time select register (OSTS) after sufficiently evaluating the oscillation stabilization time with the resonator to be used.

Remark When using the X1 and XT1 oscillator, refer to **5.4 System Clock Oscillator** in the RL78/L1A User's Manual.

2.2.2 On-chip oscillator characteristics

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Oscillators	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
High-speed on-chip oscillator clock frequency Notes 1, 2	f _{HOCO}	2.7 V ≤ V _{DD} ≤ 3.6 V		1		24	MHz
		2.4 V ≤ V _{DD} ≤ 3.6 V		1		16	MHz
		1.8 V ≤ V _{DD} ≤ 3.6 V		1		8	MHz
High-speed on-chip oscillator clock frequency accuracy		-20 to +85°C	1.8 V ≤ V _{DD} ≤ 3.6 V	-1.0		+1.0	%
		-40 to -20°C	1.8 V ≤ V _{DD} ≤ 3.6 V	-1.5		+1.5	%
Low-speed on-chip oscillator clock frequency	f _{IL}				15		kHz
Low-speed on-chip oscillator clock frequency accuracy				-15		+15	%

Note 1. High-speed on-chip oscillator frequency is selected with bits 0 to 4 of the option byte (000C2H/010C2H) and bits 0 to 2 of the HOCODIV register.

Note 2. This only indicates the oscillator characteristics. Refer to **AC Characteristics** for instruction execution time.

2.3 DC Characteristics

2.3.1 Pin characteristics

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Items	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Output current, high Note 1	IOH1	Per pin for P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130			-10.0 Note 2	mA
		Total of P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130 (When duty = 70% Note 3)	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V		-15.0	mA
	IOH2	Per pin for P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V		-0.1 Note 2	mA
		Total of P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154 (When duty = 70% Note 3)	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V		-1.6	mA

Note 1. Value of current at which the device operation is guaranteed even if the current flows from the VDD pin(IOH1), AVDD pin(IOH2) to an output pin.

Note 2. However, do not exceed the total current value.

Note 3. Specification under conditions where the duty factor is 70%.

The output current value that has changed the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = $(IOH \times 0.7)/(n \times 0.01)$

<Example> Where n = 50% and IOH = -10.0 mA

$$\text{Total output current of pins} = (-10.0 \times 0.7)/(50 \times 0.01) = -14.0 \text{ mA}$$

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Caution P00-P02, P11, P12, P14, P35-P37, P40, P41, P43, P44, P80, P81 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Items	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Output current, low Note 1	IOL1	Per pin for P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130			20.0 Note 2	mA
		Per pin for P60 and P61			15.0 Note 2	mA
		Total of P40 to P44 (When duty = 70% Note 3)	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V		15.0	mA
			1.8 V ≤ AVDD ≤ VDD < 2.7 V		9.0	mA
		Total of P00 to P07, P11 to P17, P30 to P37, P50 to P57, P60, P61, P70 to P77, P80, P81, P125 to P127, P130 (When duty = 70% Note 3)	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V		35.0	mA
			1.8 V ≤ AVDD ≤ VDD < 2.7 V		20.0	mA
		Total of all pins (When duty = 70% Note 3)			50.0	mA
	IOL2	Per pin for P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V		0.4 Note 2	mA
		Total of P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154 (When duty = 70% Note 3)	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V		6.4	mA

Note 1. Value of current at which the device operation is guaranteed even if the current flows from an output pin to the VSS pin (IOL1), AVss pin (IOL2).

Note 2. However, do not exceed the total current value.

Note 3. Specification under conditions where the duty factor is 70%.

The output current value that has changed the duty ratio can be calculated with the following expression (when changing the duty factor from 70% to n%).

- Total output current of pins = $(I_{OL} \times 0.7)/(n \times 0.01)$

<Example> Where n = 50% and IOL = 10.0 mA

$$\text{Total output current of pins} = (10.0 \times 0.7)/(50 \times 0.01) = 14.0 \text{ mA}$$

However, the current that is allowed to flow into one pin does not vary depending on the duty factor. A current higher than the absolute maximum rating must not flow into one pin.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Items	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage, high	VIH1	Port P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80 to P81, P125 to P127	Normal input buffer	0.8 VDD		VDD	V
	VIH2	For TTL mode supported ports	TTL input buffer 3.3 V ≤ VDD ≤ 3.6 V	2.0		VDD	V
			TTL input buffer 1.8 V ≤ VDD < 3.3 V	1.50		VDD	V
	VIH3	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	0.7 AVDD		AVDD	V	
	VIH4	P60, P61	0.7 VDD		6.0	V	
Input voltage, low	VL1	Port P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80 to P81, P125 to P127	Normal input buffer	0		0.2 VDD	V
	VL2	For TTL mode supported ports	TTL input buffer 3.3 V ≤ VDD ≤ 3.6 V	0		0.5	V
			TTL input buffer 1.8 V ≤ VDD < 3.3 V	0		0.32	V
	VL3	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	0		0.3 AVDD	V	
	VL4	P60, P61	0		0.3 VDD	V	
	VL5	P121 to P124, P137, EXCLK, EXCLKS, <u>RESET</u>	0		0.2 VDD	V	

Caution The maximum value of VIH of pins P00 to P02, P11, P12, P14, P35 to P37, P40, P41, P43, P44, P80, P81 is VDD, even in the N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Items	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Output voltage, high	VOH1	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOH = -2.0 mA	VDD - 0.6		V
			1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOH = -1.5 mA	VDD - 0.5		V
	VOH2	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOH = -100 μA	AVDD - 0.5		V
Output voltage, low	VOL1	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P70 to P77, P80, P81, P125 to P127, P130	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 3.0 mA		0.6	V
			2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 1.5 mA		0.4	V
			1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 0.6 mA		0.4	V
	VOL2	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 400 μA		0.4	V
	VOL3	P60, P61	2.7 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 3.0 mA		0.4	V
			1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, IOL = 2.0 mA		0.4	V

Caution P00 to P02, P11, P12, P14, P35 to P37, P40, P41, P43, P44, P80, P81 do not output high level in N-ch open-drain mode.

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Input leakage current, high	I _{LIH1}	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P60, P61, P70 to P77, P80, P81, P125 to P127, P137,_RESET	VI = VDD				1	µA
	I _{LIH3}	P121 to P124 (X1, X2, EXCLK, XT1, XT2, EXCLKS)	VI = VDD	In input port or external clock input			1	µA
				In resonator connection			10	µA
	I _{LIH4}	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	VI = AVDD				1	µA
Input leakage current, low	I _{LIL1}	P00 to P07, P11 to P17, P30 to P37, P40 to P44, P50 to P57, P60, P61, P70 to P77, P80, P81, P125 to P127, P137,_RESET	VI = VSS				-1	µA
	I _{LIL3}	P121 to P124 (X1, X2, EXCLK, XT1, XT2, EXCLKS)	VI = VSS	In input port or external clock input			-1	µA
				In resonator connection			-10	µA
	I _{LIL4}	P20, P21, P23 to P27, P100, P101, P103 to P107, P140 to P143, P150, P152 to P154	VI = AVSS				-1	µA
On-chip pull-up resistance	R _{U1}	P00 to P07, P11 to P17, P30 to P37, P50 to P57, P70 to P77, P80, P81, P125 to P127	VI = VSS	2.4 V ≤ VDD ≤ 3.6 V	10	20	100	kΩ
	R _{U2}	P40 to P44		1.8 V ≤ VDD < 2.4 V	10	30	100	

Remark Unless specified otherwise, the characteristics of alternate-function pins are the same as those of the port pins.

2.3.2 Supply current characteristics

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = 0 V)

(1/2)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
Supply current Note 1	I _{DD1}	Operating mode HS (high-speed main) mode Note 5	f _H = 24 MHz Note 3	Basic operation	V _{DD} = 3.6 V		1.7		mA
					V _{DD} = 3.0 V		1.7		
				Normal operation	V _{DD} = 3.6 V		3.6	6.1	
					V _{DD} = 3.0 V		3.6	6.1	
			f _H = 16 MHz Note 3	Normal operation	V _{DD} = 3.6 V		2.7	4.7	
					V _{DD} = 3.0 V		2.7	4.7	
		LS (low-speed main) mode Note 5	f _H = 8 MHz Note 3	Normal operation	V _{DD} = 3.6 V		1.2	2.1	mA
					V _{DD} = 3.0 V		1.2	2.1	
		HS (high-speed main) mode Note 5	f _{MX} = 20 MHz Note 2, V _{DD} = 3.6 V	Normal operation	Square wave input		3.0	5.1	mA
					Resonator connection		3.2	5.2	
			f _{MX} = 20 MHz Note 2, V _{DD} = 3.0 V	Normal operation	Square wave input		2.9	5.1	
					Resonator connection		3.2	5.2	
			f _{MX} = 16 MHz Note 2, V _{DD} = 3.6 V	Normal operation	Square wave input		2.5	4.4	
					Resonator connection		2.7	4.5	
			f _{MX} = 16 MHz Note 2, V _{DD} = 3.0 V	Normal operation	Square wave input		2.5	4.4	
					Resonator connection		2.7	4.5	
			f _{MX} = 10 MHz Note 2, V _{DD} = 3.6 V	Normal operation	Square wave input		1.9	3.0	mA
					Resonator connection		1.9	3.0	
		LS (low-speed main) mode Note 5	f _{MX} = 10 MHz Note 2, V _{DD} = 3.0 V	Normal operation	Square wave input		1.9	3.0	
					Resonator connection		1.9	3.0	
			f _{MX} = 8 MHz Note 2, V _{DD} = 3.6 V	Normal operation	Square wave input		1.1	2.0	μA
					Resonator connection		1.1	2.0	
			f _{MX} = 8 MHz Note 2, V _{DD} = 3.0 V	Normal operation	Square wave input		1.1	2.0	
					Resonator connection		1.1	2.0	
		Subsystem clock operation	f _{SUB} = 32.768 kHz Note 4 TA = -40°C	Normal operation	Square wave input		4.0	5.4	μA
					Resonator connection		4.3	5.4	
			f _{SUB} = 32.768 kHz Note 4 TA = +25°C	Normal operation	Square wave input		4.0	5.4	
					Resonator connection		4.3	5.4	
			f _{SUB} = 32.768 kHz Note 4 TA = +50°C	Normal operation	Square wave input		4.1	7.1	
					Resonator connection		4.4	7.1	
			f _{SUB} = 32.768 kHz Note 4 TA = +70°C	Normal operation	Square wave input		4.3	8.7	μA
					Resonator connection		4.7	8.7	
			f _{SUB} = 32.768 kHz Note 4 TA = +85°C	Normal operation	Square wave input		4.7	12.0	
					Resonator connection		5.2	12.0	

(Notes and Remarks are listed on the next page.)

Note 1. Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD}, or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, D/A converter, rail to rail OPA (with analog MUX), General-purpose OPA, voltage reference, low-resistance switch, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.

Note 2. When high-speed on-chip oscillator and subsystem clock are stopped.

Note 3. When high-speed system clock and subsystem clock are stopped.

Note 4. When high-speed on-chip oscillator and high-speed system clock are stopped. When AMPHS1 = 1 (Ultra-low power consumption oscillation). However, not including the current flowing into the real-time clock 2, 12-bit interval timer, 8-bit interval timer, and watchdog timer.

Note 5. Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.

HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 24 MHz

2.4 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 16 MHz

LS (low-speed main) mode: 1.8 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 8 MHz

Remark 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

Remark 2. f_{iH}: Frequency when the high-speed on-chip oscillator (24 MHz max.)

Remark 3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

Remark 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = 0 V)

(2/2)

Parameter	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Supply current Note 1	I _{DD2} Note 2	HALT mode	HS (high-speed main) mode Note 7	f _{IH} = 24 MHz Note 4	V _{DD} = 3.6 V	0.42	1.83	mA
					V _{DD} = 3.0 V	0.42	1.83	
				f _{IH} = 16 MHz Note 4	V _{DD} = 5.0 V	0.39	1.38	
					V _{DD} = 3.0 V	0.39	1.38	
			LS (low-speed main) mode Note 7	f _{IH} = 8 MHz Note 4	V _{DD} = 3.0 V	0.25	0.71	mA
					V _{DD} = 2.0 V	0.25	0.71	
			HS (high-speed main) mode Note 7	f _{MX} = 20 MHz Note 3, V _{DD} = 3.6 V	Square wave input	0.26	1.55	mA
					Resonator connection	0.4	1.68	
				f _{MX} = 20 MHz Note 3, V _{DD} = 3.0 V	Square wave input	0.25	1.55	
					Resonator connection	0.4	1.68	
				f _{MX} = 16 MHz Note 3, V _{DD} = 3.6 V	Square wave input	0.23	1.22	
					Resonator connection	0.36	1.39	
				f _{MX} = 16 MHz Note 3, V _{DD} = 3.0 V	Square wave input	0.22	1.22	
					Resonator connection	0.35	1.39	
				f _{MX} = 10 MHz Note 3, V _{DD} = 3.0 V	Square wave input	0.18	0.82	
					Resonator connection	0.28	0.90	
				f _{MX} = 10 MHz Note 3, V _{DD} = 2.0 V	Square wave input	0.18	0.81	
					Resonator connection	0.28	0.89	
			LS (low-speed main) mode Note 7	f _{MX} = 8 MHz Note 3, V _{DD} = 3.0 V	Square wave input	0.09	0.51	mA
					Resonator connection	0.15	0.56	
				f _{MX} = 8 MHz Note 3, V _{DD} = 2.0 V	Square wave input	0.10	0.52	
					Resonator connection	0.15	0.57	
			Subsystem clock operation	f _{SUB} = 32.768 kHz Note 5 TA = -40°C	Square wave input	0.32	0.75	µA
					Resonator connection	0.51	0.83	
				f _{SUB} = 32.768 kHz Note 5 TA = +25°C	Square wave input	0.41	0.83	
					Resonator connection	0.62	1.00	
				f _{SUB} = 32.768 kHz Note 5 TA = +50°C	Square wave input	0.52	1.17	
					Resonator connection	0.75	1.36	
				f _{SUB} = 32.768 kHz Note 5 TA = +70°C	Square wave input	0.82	1.97	
					Resonator connection	1.08	2.16	
				f _{SUB} = 32.768 kHz Note 5 TA = +85°C	Square wave input	1.38	3.37	
					Resonator connection	1.62	3.56	
I _{DD3} Note 6	I _{DD3} Note 8	STOP mode	T _A = -40°C			0.16	0.51	µA
			T _A = +25°C			0.22	0.51	
			T _A = +50°C			0.27	1.10	
			T _A = +70°C			0.37	1.90	
			T _A = +85°C			0.6	3.30	

(Notes and Remarks are listed on the next page.)

- Note 1.** Total current flowing into V_{DD}, including the input leakage current flowing when the level of the input pin is fixed to V_{DD} or V_{SS}. The values below the MAX. column include the peripheral operation current. However, not including the current flowing into the LCD controller/driver, A/D converter, D/A converter, all to rail OPA (with analog MUX), General-purpose OPA, voltage reference, low-resistance switch, comparator, LVD circuit, I/O port, and on-chip pull-up/pull-down resistors and the current flowing during data flash rewrite.
- Note 2.** During HALT instruction execution by flash memory.
- Note 3.** When high-speed on-chip oscillator and subsystem clock are stopped.
- Note 4.** When high-speed system clock and subsystem clock are stopped.
- Note 5.** When high-speed on-chip oscillator and high-speed system clock are stopped. When RTCLPC = 1 and setting ultra-low current consumption (AMPHS1 = 1). The current flowing into the real-time clock 2 is included. However, not including the current flowing into the 12-bit interval timer, 8-bit interval timer, and watchdog timer.
- Note 6.** Not including the current flowing into the real-time clock 2, 12-bit interval timer, 8-bit interval timer, and watchdog timer.
- Note 7.** Relationship between operation voltage width, operation frequency of CPU and operation mode is as below.
HS (high-speed main) mode: 2.7 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 24 MHz
2.4 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 16 MHz
LS (low-speed main) mode: 1.8 V ≤ V_{DD} ≤ 3.6 V @ 1 MHz to 8 MHz
- Note 8.** Regarding the value for current to operate the subsystem clock in STOP mode, refer to that in HALT mode.

Remark 1. f_{MX}: High-speed system clock frequency (X1 clock oscillation frequency or external main system clock frequency)

Remark 2. f_{iH}: Frequency when the high-speed on-chip oscillator (24 MHz max.)

Remark 3. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

Remark 4. Except subsystem clock operation, temperature condition of the TYP. value is TA = 25°C

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Low-speed on-chip oscillator operating current	IFIL Note 1				0.20		µA
RTC2 operating current	IRTC Notes 1, 3	fSUB = 32.768 kHz			0.02		µA
12-bit interval timer operating current	ITMKA Notes 1, 2, 4	fSUB = 32.768 kHz			0.02		µA
8-bit interval timer operating current	ITMRT Notes 1, 20	fSUB = 32.768 kHz	8-bit counter mode × 2-channel operation		0.12		µA
			16-bit counter mode operation		0.10		µA
Watchdog timer operating current	IWDT Notes 1, 5	fIL = 15 kHz			0.22		µA
A/D converter operating current	IADC Notes 6, 7	AVDD = 3.0 V, when conversion at maximum speed			0.7	1.7	mA
A/D converter AVREF(+) current	IADREF Note 8	AVDD = 3.0 V, HVSEL[1:0] = 00B Note 7			40	80	µA
		AVDD = 3.0 V, HVSEL[1:0] = 01B Note 10			40	80	
Internal reference voltage (1.45 V) current	IADREF Notes 1, 9				85		µA
Temperature sensor operating current	ITMPS Note 1				85		µA
D/A converter operating current	IDAC Notes 7, 11	Per D/A converter channel			0.4	0.8	mA
D/A converter AVREF(+) current	IDAREF Note 10	AVREFP = 3.0 V, REF[2:0] = 110B, Per channel			35	80	µA
Comparator operating current	ICMP Notes 1, 12	VDD = 3.6 V, Regulator output voltage = 2.1 V	Window mode		7.0		µA
			Comparator high-speed mode		2.6		µA
			Comparator low-speed mode		1.2		µA
		VDD = 3.6 V, Regulator output voltage = 1.8 V	Window mode		4.10		µA
			Comparator high-speed mode		1.5		µA
			Comparator low-speed mode		0.9		µA
General-purpose operational amplifier operating current (for 1 unit)	IAMP1 Notes 7, 19	AVDD = 3.0	Low-power consumption mode		2	4	µA
			High-speed mode		140	280	µA
Rail to rail operational amplifier operating current (for 1 unit)	IAMP2 Notes 7, 19	AVDD = 3.0	Low-power consumption mode		10	16	µA
			High-speed mode		210	350	µA
LVD operating current	ILVI Notes 1, 13				0.06		µA
Self-programming operating current	IFSP Notes 1, 14				2.0	12.2	mA
BGO operating current	IBGO Notes 1, 15				2.0	12.2	mA
SNOOZE operating current	ISNOZ Note 1	CSI/UART operation			0.70	0.84	mA
Voltage reference	IVREF	AVDD = VDD = 3.0 V				40	µA

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, VSS = 0 V)

Parameter	Symbol	Conditions				MIN.	TYP.	MAX.	Unit
LCD operating current	ILCD1 Notes 17, 18	External resistance division method	f _{LCD} = f _{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V _{DD} = 3.6 V, V _{L4} = 3.6 V		0.14		µA
	ILCD2 Note 17	Internal voltage boosting method	f _{LCD} = f _{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V _{DD} = 3.0 V, V _{L4} = 3.0 V (VLCD = 04H)		0.61		µA
	ILCD3 Note 17	Capacitor split method	f _{LCD} = f _{SUB} LCD clock = 128 Hz	1/3 bias 4-time slice	V _{DD} = 3.0 V, V _{L4} = 3.0 V		0.12		µA

(Notes and Remarks are listed on the next page.)

- Note 1.** Current flowing to V_{DD}.
- Note 2.** When high speed on-chip oscillator and high-speed system clock are stopped.
- Note 3.** Current flowing only to the real-time clock 2 (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{RTC}, when the real-time clock 2 operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added. I_{DD2} subsystem clock operation includes the operational current of the real-time clock 2.
- Note 4.** Current flowing only to the 12-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{TMKA}, when the 12-bit interval timer operates in operation mode or HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added. I_{DD2} subsystem clock operation includes the operational current of the 12-bit interval timer.
- Note 5.** Current flowing only to the watchdog timer (including the operating current of the low-speed on-chip oscillator). The current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{WDT} when the watchdog timer operates in STOP mode.
- Note 6.** Current flowing only to the A/D converter. The supply current of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2} and I_{AADC}, I_{AVREF}, I_{ADREF} when the A/D converter operates in an operation mode or the HALT mode.
- Note 7.** Current flowing to the AV_{DD}.
- Note 8.** Current flowing from the reference voltage source of A/D converter.
- Note 9.** Operation current flowing to the internal reference voltage.
- Note 10.** Current flowing to the AV_{REFP}.
- Note 11.** Current flowing only to the D/A converter. The current value of the RL78 microcontrollers is the sum of I_{DD1} or I_{DD2} and I_{DA} when the D/A converter operates in an operation mode or the HALT mode.
- Note 12.** Current flowing only to the comparator circuit. The current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{CMP} when the comparator circuit operates in the Operating, HALT or STOP mode.
- Note 13.** Current flowing only to the LVD circuit. The current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{LVI} when the LVD circuit operates in the Operating, HALT or STOP mode.
- Note 14.** Current flowing only during self-programming.
- Note 15.** Current flowing only during data flash rewrite.
- Note 16.** For shift time to the SNOOZE mode, see **24.3.3 SNOOZE mode** in the RL78/L1A User's Manual.RL78 microcontrollers
- Note 17.** Current flowing only to the LCD controller/driver (V_{DD} pin). The current value of the RL78 microcontrollers is the sum of the LCD operating current (I_{LCD1}, I_{LCD2} or I_{LCD3}) to the supply current (I_{DD1}, or I_{DD2}) when the LCD controller/driver operates in an operation mode or HALT mode. Not including the current that flows through the LCD panel.
- Note 18.** Not including the current that flows through the external divider resistor divider resistor.
- Note 19.** Current flowing only to the operational amplifier. The current value of the RL78 microcontrollers is the sum of I_{DD1}, I_{DD2} or I_{DD3} and I_{AMP} when the operational amplifier operates in the operating mode, HALT mode, or STOP mode.
- Note 20.** Current flowing only to the 8-bit interval timer (excluding the operating current of the low-speed on-chip oscillator and the XT1 oscillator). The supply current of the RL78 microcontrollers is the sum of the values of either I_{DD1} or I_{DD2}, and I_{IT}, when the 8-bit interval timer operates in the operating mode or HALT mode. When the low-speed on-chip oscillator is selected, I_{FIL} should be added.

Remark 1. fil: Low-speed on-chip oscillator clock frequency

Remark 2. f_{SUB}: Subsystem clock frequency (XT1 clock oscillation frequency)

Remark 3. f_{CLK}: CPU/peripheral hardware clock frequency

Remark 4. Temperature condition of the TYP. value is TA = 25°C

2.4 AC Characteristics

2.4.1 Basic operation

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = 0 V)

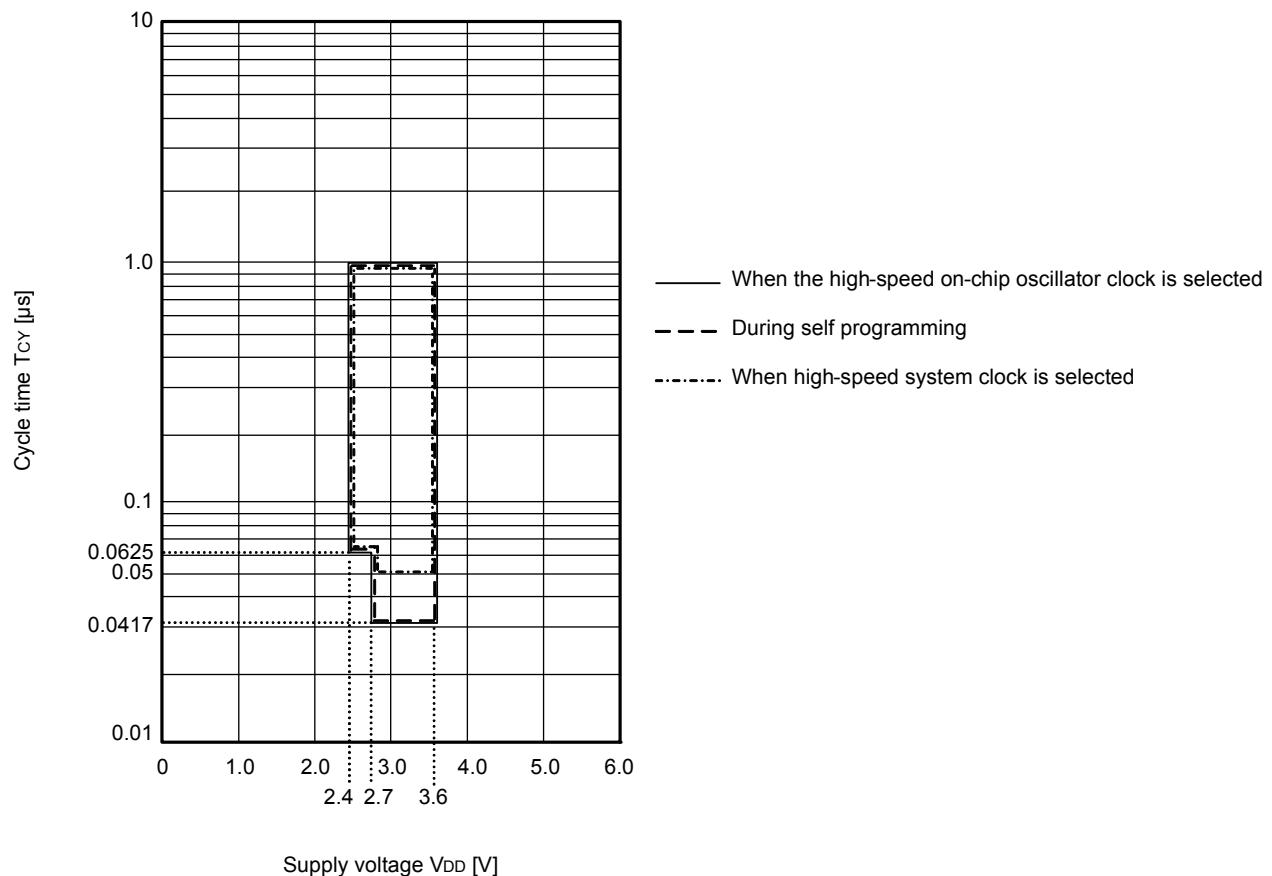
Items	Symbol	Conditions			MIN.	TYP.	MAX.	Unit
Instruction cycle (minimum instruction execution time)	Tcv	Main system clock (fMAIN) operation	HS (high-speed main) mode	2.7 V ≤ VDD ≤ 3.6 V	0.0417		1	μs
			2.4 V ≤ VDD < 2.7 V	0.0625			1	μs
		LS (low-speed main) mode	1.8 V ≤ VDD ≤ 3.6 V	0.125			1	μs
		Subsystem clock (fsUB) operation	1.8 V ≤ VDD ≤ 3.6 V	28.5	30.5	31.3		μs
		In the self-programming mode	HS (high-speed main) mode	2.7 V ≤ VDD ≤ 3.6 V	0.0417		1	μs
			2.4 V ≤ VDD < 2.7 V	0.0625			1	μs
		LS (low-speed main) mode	1.8 V ≤ VDD ≤ 3.6 V	0.125			1	μs
External main system clock frequency	fEX	EXCLK		2.7 V ≤ VDD ≤ 3.6 V	1.0		20.0	MHz
				2.4 V ≤ VDD < 2.7 V	1.0		16.0	MHz
				1.8 V ≤ VDD < 2.7 V	1.0		8.0	MHz
	fEXT	EXCLKS			32		35	kHz
External main system clock input high-level width, low-level width	texH, texL	EXCLK		2.7 V ≤ VDD ≤ 3.6 V	24			ns
				2.4 V ≤ VDD < 2.7 V	30			ns
				1.8 V ≤ VDD < 2.7 V	60			ns
	texHS, texLS	EXCLKS			13.7			μs
Timer input high-level width, low-level width	tTH, tTL	TI00 to TI07			1/fMCK + 10			ns
Timer output frequency	fTO	TO00 to TO07	HS (high-speed main) mode	2.7 V ≤ VDD ≤ 3.6 V			8	MHz
			2.4 V ≤ VDD < 2.7 V				8	MHz
			LS (low-speed main) mode	1.8 V ≤ VDD ≤ 3.6 V			4	MHz
Buzzer output frequency	fpCL	PCLBUZ0, PCLBUZ1	HS (high-speed main) mode	2.7 V ≤ VDD ≤ 3.6 V			8	MHz
			2.4 V ≤ VDD < 2.7 V				8	MHz
			LS (low-speed main) mode	1.8 V ≤ VDD ≤ 3.6 V			4	MHz
Interrupt input high-level width, low-level width	tINTH, tINTL	INTP0 to INTP7		1.8 V ≤ VDD ≤ 3.6 V	1			μs
Key interrupt input low-level width	tKR	KR0 to KR7		1.8 V ≤ VDD ≤ 3.6 V	250			ns
RESET low-level width	tRSL	RESET			10			μs

Remark fMCK: Timer array unit operation clock frequency

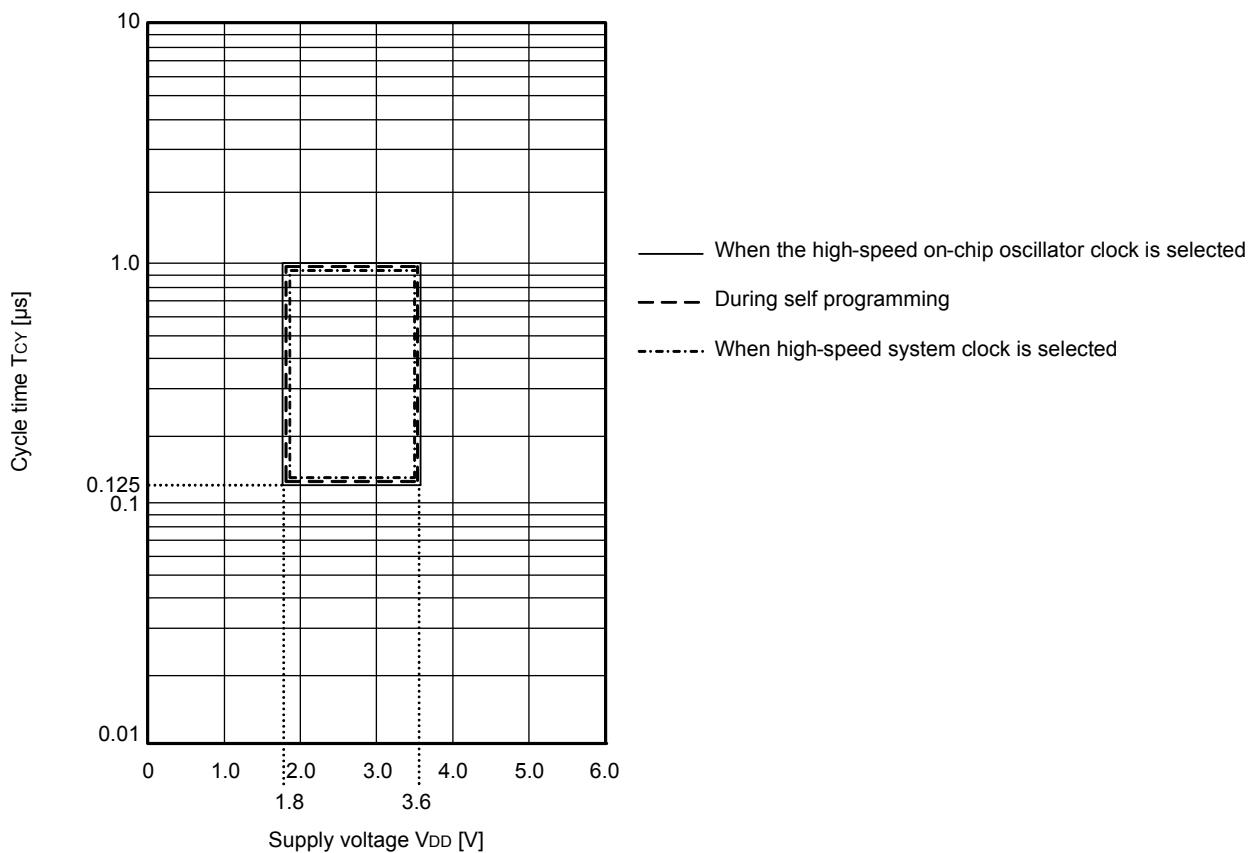
(Operation clock to be set by the CKSmn bit of timer mode register mn (TMRmn). m: Unit number (m = 0), n: Channel number (n = 0 to 7))

Minimum Instruction Execution Time during Main System Clock Operation

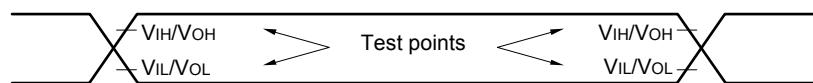
T_{CY} vs V_{DD} (HS (high-speed main) mode)



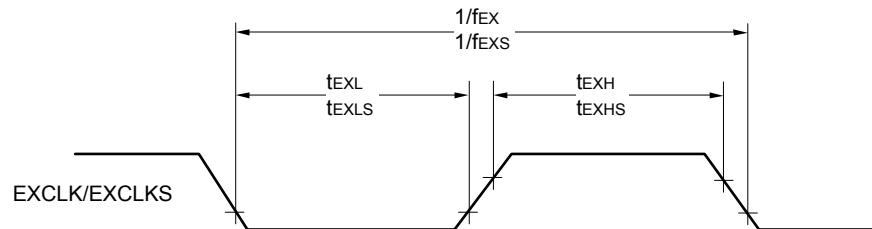
TCY vs VDD (LS (low-speed main) mode)



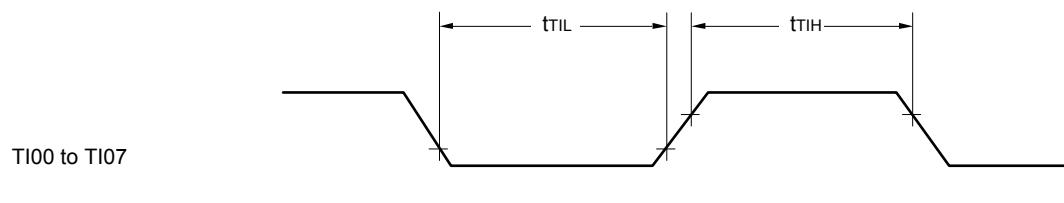
AC Timing Test Points



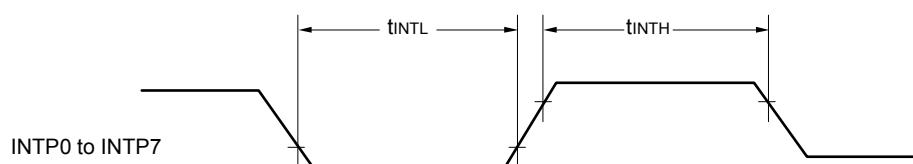
External System Clock Timing



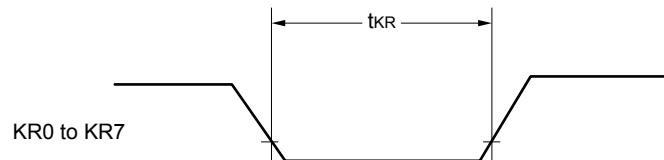
TI/TO Timing



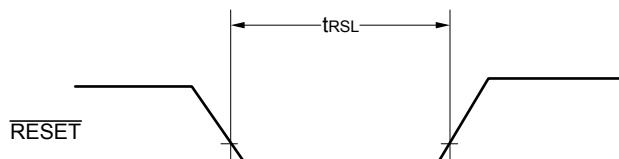
Interrupt Request Input Timing



Key Interrupt Input Timing

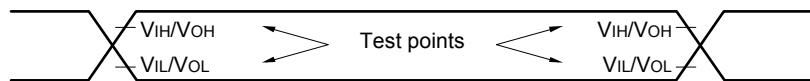


RESET Input Timing



2.5 Peripheral Functions Characteristics

AC Timing Test Points



2.5.1 Serial array unit

(1) During communication at same potential (UART mode)

(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate Note 1		2.7 V ≤ VDD ≤ 3.6 V		fMCK/6 Note 2		fMCK/6	bps
		Theoretical value of the maximum transfer rate fMCK = fCLK Note 3		4.0		1.3	Mbps
		2.4 V ≤ VDD ≤ 3.6 V		fMCK/6 Note 2		fMCK/6	bps
		Theoretical value of the maximum transfer rate fMCK = fCLK Note 3		2.6		1.3	Mbps
		1.8 V ≤ VDD ≤ 3.6 V	—	—	fMCK/6 Note 2	bps	
		Theoretical value of the maximum transfer rate fMCK = fCLK Note 3	—	—	1.3	Mbps	

Note 1. Transfer rate in the SNOOZE mode is 4800 bps only.

Note 2. The following conditions are required for low voltage interface.

2.4 V ≤ VDD < 2.7 V: MAX. 2.6 Mbps

1.8 V ≤ VDD < 2.4 V: MAX. 1.3 Mbps

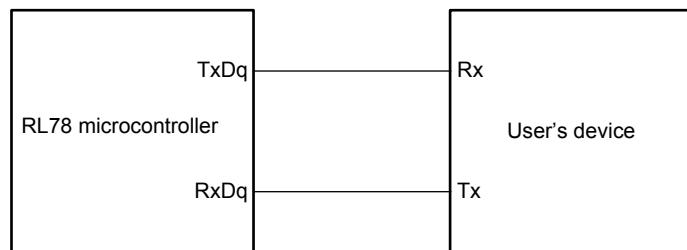
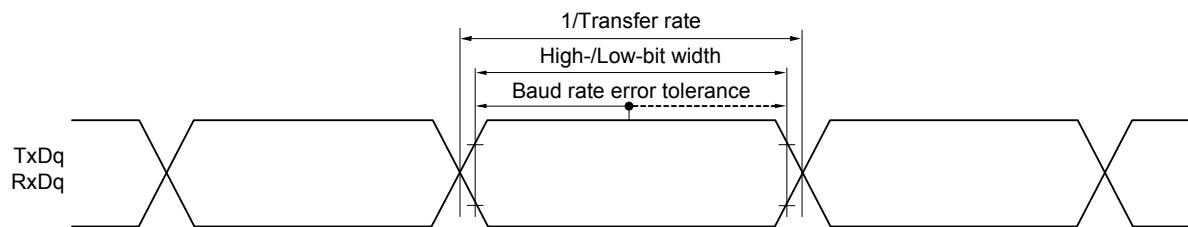
Note 3. The maximum operating frequencies of the CPU/peripheral hardware clock (fCLK) are:

HS (high-speed main) mode: 24 MHz (2.7 V ≤ VDD ≤ 3.6 V)

16 MHz (2.4 V ≤ VDD ≤ 3.6 V)

LS (low-speed main) mode: 8 MHz (1.8 V ≤ VDD ≤ 3.6 V)

Caution Select the normal input buffer for the RxDq pin and the normal output mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg).

UART mode connection diagram (during communication at same potential)**UART mode bit width (during communication at same potential) (reference)**

Remark 1. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)

Remark 2. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(2) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

(TA = -40 to +85 °C, 2.7 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	tkCY1	tkCY1 ≥ fCLK/2	2.7 V ≤ VDD ≤ 3.6 V	167		250		ns
SCKp high-/low-level width	tkL1	2.7 V ≤ VDD ≤ 3.6 V		tkCY1/2 - 10		tkCY1/2 - 50		ns
Slp setup time (to SCKp↑) Note 1	tsIK1	2.7 V ≤ VDD ≤ 3.6 V		33		110		ns
Slp hold time (from SCKp↑) Note 2	tkSI1	2.7 V ≤ VDD ≤ 3.6 V		10		10		ns
Delay time from SCKp↓ to SOp output Note 3	tkSO1	C = 20 pF Note 4			10		10	ns

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 4. C is the load capacitance of the SCKp and SOp output lines.

Caution Select the normal input buffer for the Slp pin and the normal output mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. p: CSI number (p = 00), m: Unit number (m = 0), n: Channel number (n = 0), g: PIM and POM number (g = 4)

Remark 2. fmCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

**(3) During communication at same potential (CSI mode) (master mode, SCKp... internal clock output)
(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)**

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t _{KCY1}	t _{KCY1} ≥ f _{CLK} /4	2.7 V ≤ V _{DD} ≤ 3.6 V	167		500		ns
			2.4 V ≤ V _{DD} ≤ 3.6 V	250		500		ns
			1.8 V ≤ V _{DD} ≤ 3.6 V	—		500		ns
SCKp high-/low-level width	t _{Kh1} , t _{kl1}	2.7 V ≤ V _{DD} ≤ 3.6 V		t _{KCY1/2} - 18		t _{KCY1/2} - 50		ns
		2.4 V ≤ V _{DD} ≤ 3.6 V		t _{KCY1/2} - 38		t _{KCY1/2} - 50		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V		—		t _{KCY1/2} - 50		ns
Slp setup time (to SCKp↑) Note 1	t _{slk1}	2.7 V ≤ V _{DD} ≤ 3.6 V		44		110		ns
		2.4 V ≤ V _{DD} ≤ 3.6 V		75		110		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V		—		110		ns
Slp hold time (from SCKp↑) Note 2	t _{ksl1}	2.4 V ≤ V _{DD} ≤ 3.6 V		19		19		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V		—		19		ns
Delay time from SCKp↓ to SO _P output Note 3	t _{ks01}	C = 30 pF Note 4	2.7 V ≤ V _{DD} ≤ 3.6 V		25		50	ns
			2.4 V ≤ V _{DD} ≤ 3.6 V		25		50	ns
			1.8 V ≤ V _{DD} ≤ 3.6 V		—		50	ns

Note 1. When DAP_{Mn} = 0 and CKP_{Mn} = 0, or DAP_{Mn} = 1 and CKP_{Mn} = 1. The Slp setup time becomes “to SCKp↓” when DAP_{Mn} = 0 and CKP_{Mn} = 1, or DAP_{Mn} = 1 and CKP_{Mn} = 0.

Note 2. When DAP_{Mn} = 0 and CKP_{Mn} = 0, or DAP_{Mn} = 1 and CKP_{Mn} = 1. The Slp hold time becomes “from SCKp↓” when DAP_{Mn} = 0 and CKP_{Mn} = 1, or DAP_{Mn} = 1 and CKP_{Mn} = 0.

Note 3. When DAP_{Mn} = 0 and CKP_{Mn} = 0, or DAP_{Mn} = 1 and CKP_{Mn} = 1. The delay time to SO_P output becomes “from SCKp↑” when DAP_{Mn} = 0 and CKP_{Mn} = 1, or DAP_{Mn} = 1 and CKP_{Mn} = 0.

Note 4. C is the load capacitance of the SCKp and SO_P output lines.

Caution Select the normal input buffer for the Slp pin and the normal output mode for the SO_P pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. p: CSI number (p = 00, 10, 20, 30), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3),
g: PIM and POM number (g = 0, 1, 3, 4, 8)

Remark 2. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSm_n bit of serial mode register mn (SMR_{Mn}). m: Unit number,
n: Channel number (mn = 00 to 03, 10 to 13))

**(4) During communication at same potential (CSI mode) (slave mode, SCKp... external clock input)
(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)**

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 5	tkCY2	2.7 V ≤ VDD ≤ 3.6 V	fMCK > 16 MHz	8/fMCK		—		ns
			fMCK ≤ 16 MHz	6/fMCK		6/fMCK		ns
		2.4 V ≤ VDD ≤ 3.6 V		6/fMCK and 500		6/fMCK and 500		ns
		1.8 V ≤ VDD ≤ 3.6 V		—		6/fMCK and 750		ns
SCKp high-/low-level width	tKH2, tKL2	2.7 V ≤ VDD ≤ 3.6 V		tkCY2/2 - 8		tkCY2/2 - 8		ns
		1.8 V ≤ VDD ≤ 3.6 V		—		tkCY2/2 - 18		ns
Slp setup time (to SCKp↑) Note 1	tsIK2	2.7 V ≤ VDD ≤ 3.6 V		1/fMCK + 20		1/fMCK + 30		ns
		2.4 V ≤ VDD ≤ 3.6 V		1/fMCK + 30		1/fMCK + 30		ns
		1.8 V ≤ VDD ≤ 3.6 V		—		1/fMCK + 30		ns
Slp hold time (from SCKp↑) Note 2	tKSI2	2.4 V ≤ VDD ≤ 3.6 V		1/fMCK + 31		1/fMCK + 31		ns
		1.8 V ≤ VDD ≤ 3.6 V		—		1/fMCK + 31		ns
Delay time from SCKp↓ to SOp output Note 3	tKS02	C = 30 pF Note 4	2.7 V ≤ VDD ≤ 3.6 V		2/fMCK + 44		2/fMCK + 110	ns
			2.4 V ≤ VDD ≤ 3.6 V		2/fMCK + 75		2/fMCK + 110	ns
			1.8 V ≤ VDD ≤ 3.6 V		—		2/fMCK + 110	ns

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp setup time becomes “to SCKp↓” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 2. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes “from SCKp↓” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes “from SCKp↑” when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 4. C is the load capacitance of the SCKp and SOp output lines.

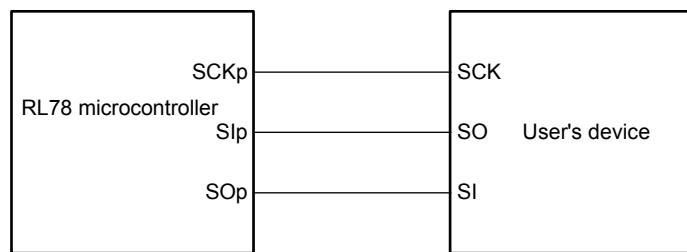
Note 5. The maximum transfer rate when using the SNOOZE mode is 1 Mbps.

Caution Select the normal input buffer for the Slp pin and the normal output mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg).

Remark 1. p: CSI number (p = 00, 10, 20, 30), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)

Remark 2. fMCK: Serial array unit operation clock frequency

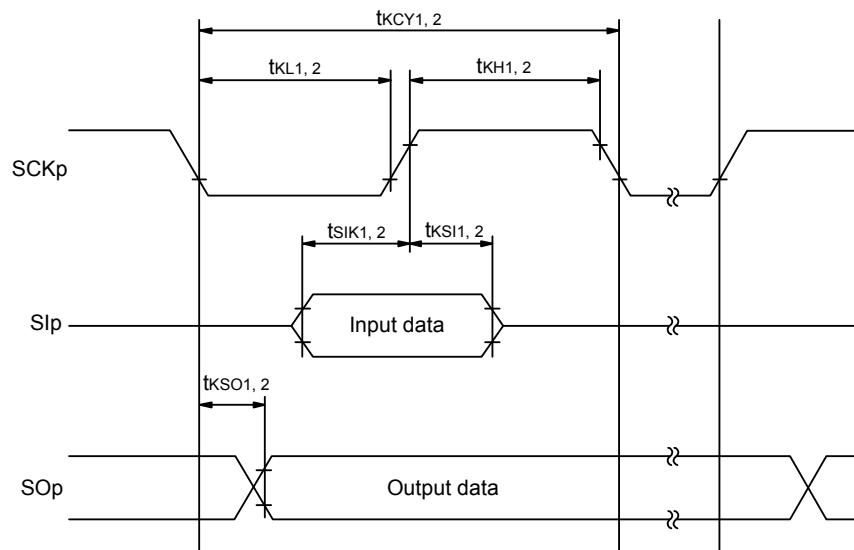
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

CSI mode connection diagram (during communication at same potential)

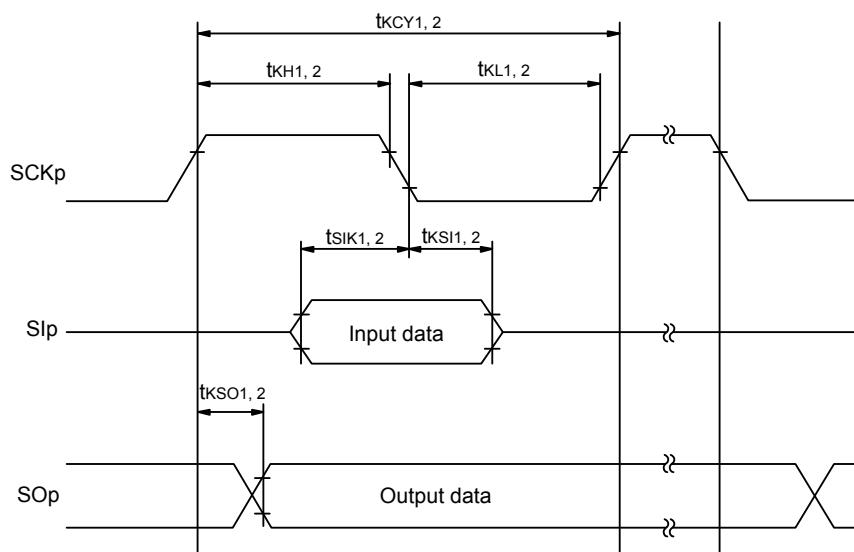
Remark 1. p: CSI number (p = 00, 10, 20, 30)

Remark 2. m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13)

CSI mode serial transfer timing (during communication at same potential)
 (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (during communication at same potential)
 (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remark 1. p: CSI number (p = 00, 10, 20, 30)

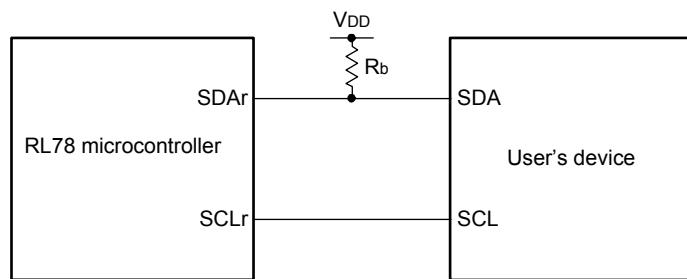
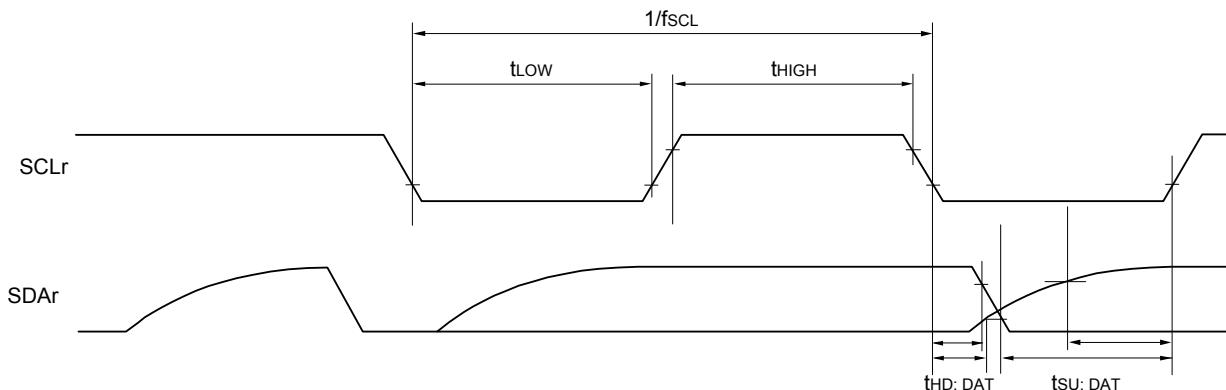
Remark 2. m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13)

(5) During communication at same potential (simplified I²C mode)(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCL _r clock frequency	f _{SCL}	2.7 V ≤ V _{DD} ≤ 3.6 V, C _b = 50 pF, R _b = 2.7 kΩ		1000 Note 1		400 Note 1	kHz
		1.8 V ≤ V _{DD} ≤ 3.6 V, C _b = 100 pF, R _b = 3 kΩ		400 Note 1		400 Note 1	kHz
		1.8 V ≤ V _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ		300 Note 1		300 Note 1	kHz
Hold time when SCL _r = "L"	t _{LOW}	2.7 V ≤ V _{DD} ≤ 3.6 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1150		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V, C _b = 100 pF, R _b = 3 kΩ	1150		1150		ns
		1.8 V ≤ V _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1550		1550		ns
Hold time when SCL _r = "H"	t _{HIGH}	2.7 V ≤ V _{DD} ≤ 3.6 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1150		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V, C _b = 100 pF, R _b = 3 kΩ	1150		1150		ns
		1.8 V ≤ V _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1550		1550		ns
Data setup time (recep- tion)	tsu: DAT	2.7 V ≤ V _{DD} ≤ 3.6 V, C _b = 50 pF, R _b = 2.7 kΩ	1/f _{MCK} + 85 Note 2		1/f _{MCK} + 145 Note 2		ns
		1.8 V ≤ V _{DD} ≤ 3.6 V, C _b = 100 pF, R _b = 3 kΩ	1/f _{MCK} + 145 Note 2		1/f _{MCK} + 145 Note 2		ns
		1.8 V ≤ V _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	1/f _{MCK} + 230 Note 2		1/f _{MCK} + 230 Note 2		ns
Data hold time (trans- mission)	t _{HD} : DAT	2.7 V ≤ V _{DD} ≤ 3.6 V, C _b = 50 pF, R _b = 2.7 kΩ	0	305	0	305	ns
		1.8 V ≤ V _{DD} ≤ 3.6 V, C _b = 100 pF, R _b = 3 kΩ	0	355	0	355	ns
		1.8 V ≤ V _{DD} < 2.7 V, C _b = 100 pF, R _b = 5 kΩ	0	405	0	405	ns

Note 1. The value must also be equal to or less than f_{MCK}/4.**Note 2.** Set the f_{MCK} value to keep the hold time of SCL_r = "L" and SCL_r = "H".

Caution Select the normal input buffer and the N-ch open drain output (V_{DD} tolerance) mode for the SDAr pin and the normal output mode for the SCL_r pin by using port input mode register g (PIMg) and port output mode register h (POMh).

Simplified I²C mode connection diagram (during communication at same potential)**Simplified I²C mode serial transfer timing (during communication at same potential)**

Remark 1. $R_b[\Omega]$: Communication line (SDAr) pull-up resistance, $C_b[F]$: Communication line (SCLr, SDAr) load capacitance

Remark 2. r: IIC number (r = 00, 10, 20, 30), g: PIM number (g = 0, 1, 3, 4, 8),

h: POM number (h = 0 to 3)

Remark 3. f_{MCK}: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number (m = 0, 1), n: Channel number (n = 0, 2), mn = 00 to 03, 10 to 13)

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode)

(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)(1/2)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
Transfer rate Notes 1, 2		reception	2.7 V ≤ VDD ≤ 3.6 V, 2.3 V ≤ Vb ≤ 2.7 V		fmck/6 Note 1		fmck/6 Note 1	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 4		4.0		1.3	Mbps
			1.8 V ≤ VDD < 3.3 V, 1.6 V ≤ Vb ≤ 2.0 V		fmck/6 Notes 1, 2, 3		fmck/6 Notes 1, 2, 3	bps
			Theoretical value of the maximum transfer rate fmck = fclk Note 4		4.0		1.3	Mbps

Note 1. Transfer rate in the SNOOZE mode is 4,800 bps only.**Note 2.** Use it with VDD ≥ Vb.**Note 3.** The following conditions are required for low voltage interface.

2.4 V ≤ VDD < 2.7 V: MAX. 2.6 Mbps

1.8 V ≤ VDD < 2.4 V: MAX. 1.3 Mbps

Note 4. The maximum operating frequencies of the CPU/peripheral hardware clock (fclk) are:

HS (high-speed main) mode: 24 MHz (2.7 V ≤ VDD ≤ 3.6 V)

16 MHz (2.4 V ≤ VDD ≤ 3.6 V)

LS (low-speed main) mode: 8 MHz (1.8 V ≤ VDD ≤ 3.6 V)

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (VDD tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.**Remark 1.** V_b[V]: Communication line voltage**Remark 2.** q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)**Remark 3.** fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(6) Communication at different potential (1.8 V, 2.5 V) (UART mode)

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)(2/2)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Transfer rate Note 2		transmission 2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V Theoretical value of the maximum transfer rate C _b = 50 pF, R _b = 2.7 kΩ, V _b = 2.3 V		Note 1		Note 1	bps
				1.2 Note 2		1.2 Note 2	Mbps
				Notes 3, 4		Notes 3, 4	bps
		Theoretical value of the maximum transfer rate C _b = 50 pF, R _b = 5.5 kΩ, V _b = 1.6 V		0.43 Note 5		0.43 Note 5	Mbps

Note 1. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.
Expression for calculating the transfer rate when 2.7 V ≤ V_{DD} ≤ 3.6 V and 2.3 V ≤ V_b ≤ 2.7 V

$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{2.0}{V_b})\}}{\left(\frac{1}{\text{Transfer rate}}\right) \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides

Note 2. This value as an example is calculated when the conditions described in the “Conditions” column are met.
Refer to Note 1 above to calculate the maximum transfer rate under conditions of the customer.

Note 3. Use it with V_{DD} ≥ V_b.

Note 4. The smaller maximum transfer rate derived by using fmck/6 or the following expression is the valid maximum transfer rate.
Expression for calculating the transfer rate when 1.8 V ≤ V_{DD} < 3.3 V and 1.6 V ≤ V_b ≤ 2.0 V

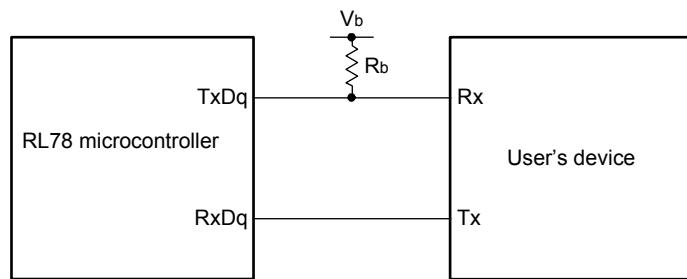
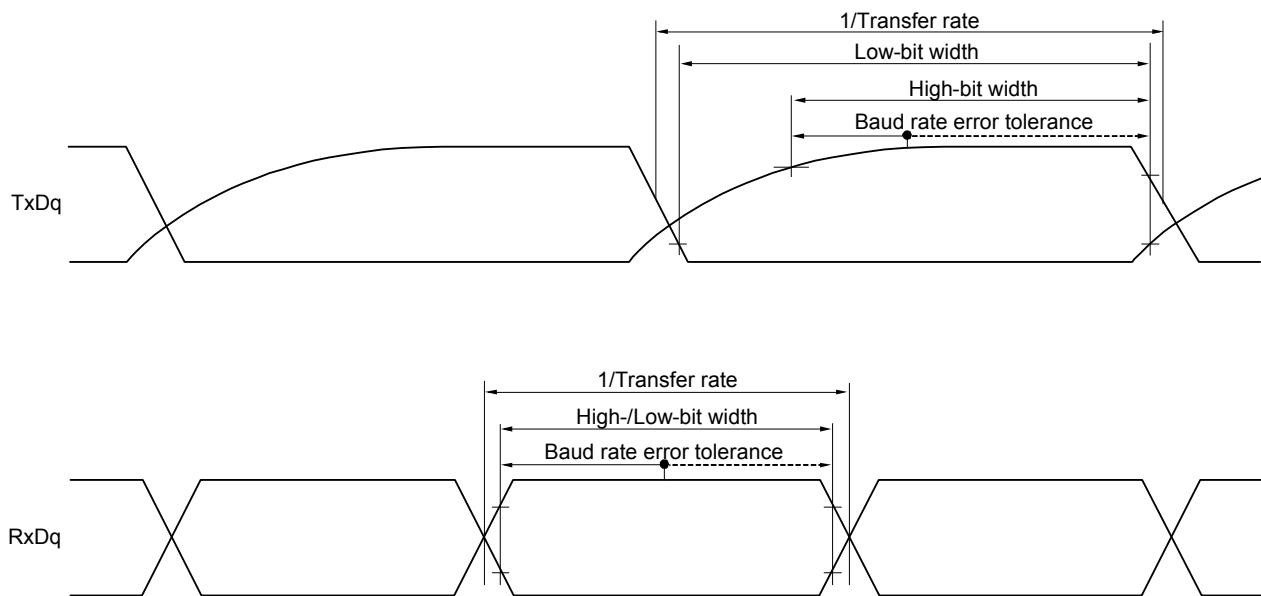
$$\text{Maximum transfer rate} = \frac{1}{\{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\} \times 3} \text{ [bps]}$$

$$\text{Baud rate error (theoretical value)} = \frac{\frac{1}{\text{Transfer rate} \times 2} - \{-C_b \times R_b \times \ln(1 - \frac{1.5}{V_b})\}}{\left(\frac{1}{\text{Transfer rate}}\right) \times \text{Number of transferred bits}} \times 100 [\%]$$

* This value is the theoretical value of the relative difference between the transmission and reception sides

Note 5. This value as an example is calculated when the conditions described in the “Conditions” column are met.
Refer to Note 4 above to calculate the maximum transfer rate under conditions of the customer.

Caution Select the TTL input buffer for the RxDq pin and the N-ch open drain output (V_{DD} tolerance) mode for the TxDq pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

UART mode connection diagram (during communication at different potential)**UART mode bit width (during communication at different potential) (reference)**

Remark 1. $R_b[\Omega]$: Communication line (TxDq) pull-up resistance, $C_b[F]$: Communication line (TxDq) load capacitance, $V_b[V]$: Communication line voltage

Remark 2. q: UART number (q = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)

Remark 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00 to 03, 10 to 13))

(7) Communication at different potential (2.5 V) (CSI mode) (master mode, SCKp... internal clock output, corresponding CSI00 only)

(TA = -40 to +85 °C, 2.7 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t _{KCY1}	t _{KCY1} ≥ 2/f _{CLK} 2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 1.4 kΩ	300		1150		ns
SCKp high-level width	t _{KH1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ	t _{KCY1} /2 - 120		t _{KCY1} /2 - 120		ns
SCKp low-level width	t _{KL1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 1.4 kΩ	t _{KCY1} /2 - 10		t _{KCY1} /2 - 50		ns
Slp setup time (to SCKp↑) Note 1	t _{SIK1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ	121		479		ns
Slp hold time (from SCKp↑) Note 1	t _{SKI1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 1.4 kΩ	10		10		ns
Delay time from SCKp↓ to SOp output Note 1	t _{KSO1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 1.4 kΩ		130		130	ns
Slp setup time (to SCKp↓) Note 2	t _{SIK1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ	33		110		ns
Slp hold time (from SCKp↓) Note 2	t _{SKI1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ	10		10		ns
Delay time from SCKp↑ to SOp output Note 2	t _{KSO1}	2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 20 pF, R _b = 2.7 kΩ		10		10	ns

Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

Note 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Caution Select the TTL input buffer for the Slp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

Remark 1. R_{b[i]}: Communication line (SCKp, SOp) pull-up resistance, C_{b[F]}: Communication line (SCKp, SOp) load capacitance, V_{b[V]}: Communication line voltage

Remark 2. p: CSI number (p = 00), m: Unit number (m = 0),

n: Channel number (n = 0), g: PIM and POM number (g = 4)

Remark 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00))

(8) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output)

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)(1/2)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCKp cycle time	t _{KCY1}	t _{KCY1} ≥ 4/f _{CLK} 2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	500 Note		1150		ns
			1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 1.8 V, C _b = 30 pF, R _b = 5.5 kΩ	1150 Note		1150	ns
SCKp high-level width	t _{KH1}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	t _{KCY1/2} - 170		t _{KCY1/2} - 170		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 30 pF, R _b = 5.5 kΩ	t _{KCY1/2} - 458		t _{KCY1/2} - 458		ns
SCKp low-level width	t _{KL1}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	t _{KCY1/2} - 18		t _{KCY1/2} - 50		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V, C _b = 30 pF, R _b = 5.5 kΩ	t _{KCY1/2} - 50		t _{KCY1/2} - 50		ns

Note Use it with V_{DD} ≥ V_b.

Caution Select the TTL input buffer for the S_{Op} pin and the N-ch open drain output (V_{DD} tolerance) mode for the S_{Op} pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the page after the next page.)

(8) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (master mode, SCKp... internal clock output)

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)(2/2)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
Slp setup time (to SCKp↑) Note 1	tsIK1	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	177		479		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ	479		479		ns
Slp hold time (from SCKp↑) Note 1	tKSI1	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	19		19		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ	19		19		ns
Delay time from SCKp↓ to SOp output Note 1	tKS01	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ		195		195	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ		483		483	ns
Slp setup time (to SCKp↓) Note 2	tsIK1	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	44		110		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ	110		110		ns
Slp hold time (from SCKp↓) Note 2	tKSI1	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ	19		19		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ	19		19		ns
Delay time from SCKp↑ to SOp output Note 2	tKS01	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V, C _b = 30 pF, R _b = 2.7 kΩ		25		25	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 3, C _b = 30 pF, R _b = 5.5 kΩ		25		25	ns

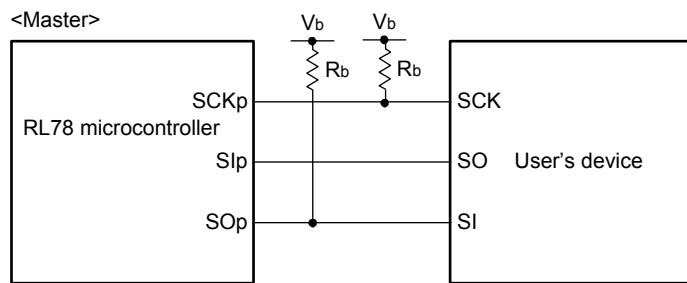
Note 1. When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.

Note 2. When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.

Note 3. Use it with V_{DD} ≥ V_b.

Caution Select the TTL input buffer for the Slp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin and SCKp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

CSI mode connection diagram (during communication at different potential)

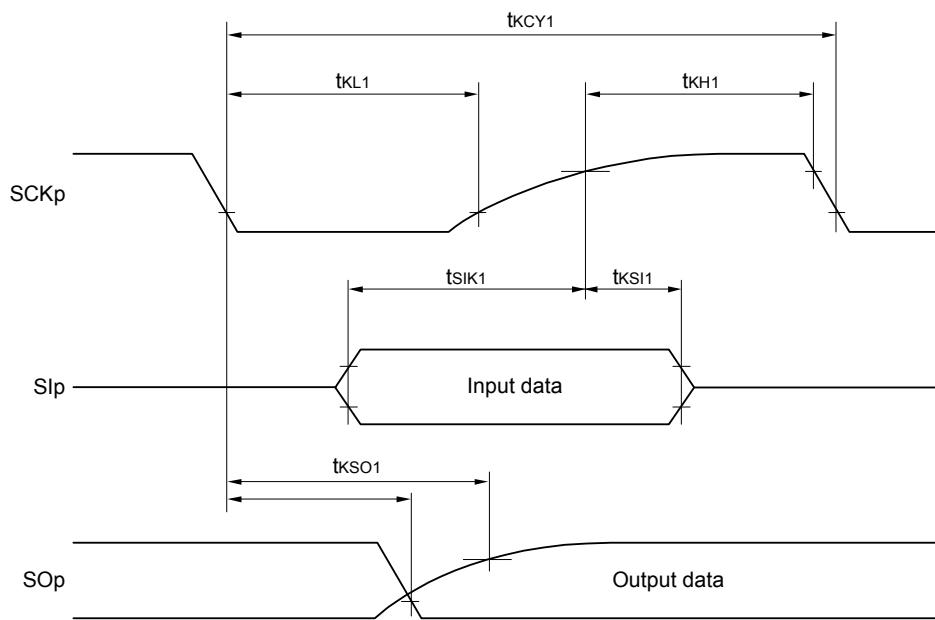
Remark 1. R_b[Ω]: Communication line (SCK_p, SO_p) pull-up resistance, C_b[F]: Communication line (SCK_p, SO_p) load capacitance, V_b[V]: Communication line voltage

Remark 2. p: CSI number (p = 00, 10, 20, 30), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)

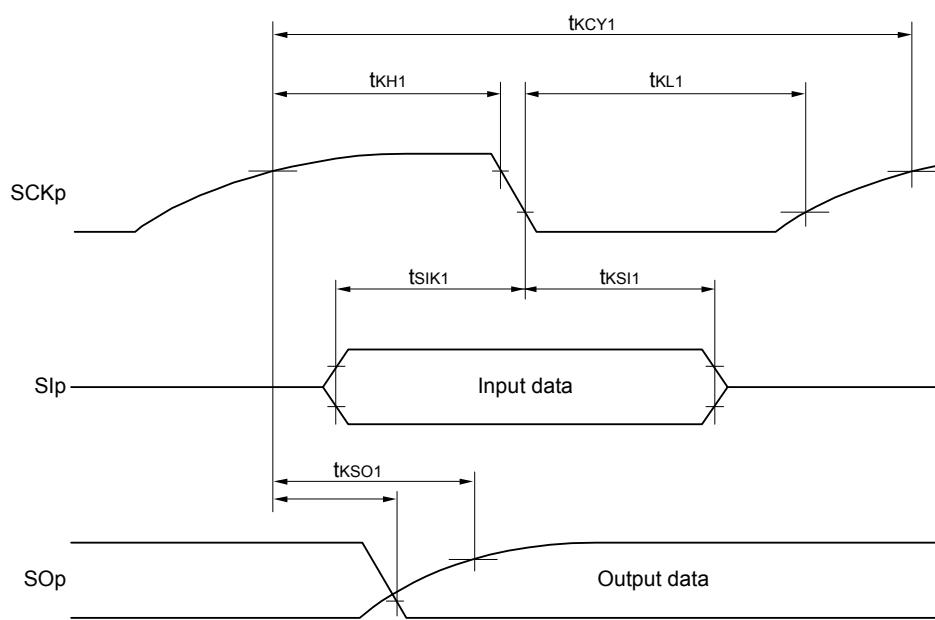
Remark 3. fmck: Serial array unit operation clock frequency
(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number, n: Channel number (mn = 00, 02, 10, 12))

CSI mode serial transfer timing (master mode) (during communication at different potential)

(When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)

**CSI mode serial transfer timing (master mode) (during communication at different potential)**

(When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remark p: CSI number ($p = 00, 10, 20, 30$), m: Unit number ($m = 0, 1$), n: Channel number ($n = 0, 2$),
g: PIM and POM number ($g = 0, 1, 3, 4, 8$)

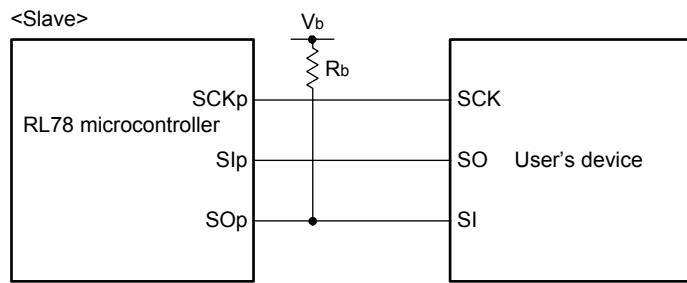
(9) Communication at different potential (1.8 V, 2.5 V) (CSI mode) (slave mode, SCKp... external clock input)

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCKp cycle time Note 1	t _{KCY2}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V	20 MHz < f _{MCK} ≤ 24 MHz	16/f _{MCK}	—	—	ns
			16 MHz < f _{MCK} ≤ 20 MHz	14/f _{MCK}	—	—	ns
			8 MHz < f _{MCK} ≤ 16 MHz	12/f _{MCK}	—	—	ns
			4 MHz < f _{MCK} ≤ 8 MHz	8/f _{MCK}	16/f _{MCK}	—	ns
			f _{MCK} ≤ 4 MHz	6/f _{MCK}	10/f _{MCK}	—	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2	20 MHz < f _{MCK} ≤ 24 MHz	36/f _{MCK}	—	—	ns
			16 MHz < f _{MCK} ≤ 20 MHz	32/f _{MCK}	—	—	ns
			8 MHz < f _{MCK} ≤ 16 MHz	26/f _{MCK}	—	—	ns
			4 MHz < f _{MCK} ≤ 8 MHz	16/f _{MCK}	16/f _{MCK}	—	ns
			f _{MCK} ≤ 4 MHz	10/f _{MCK}	10/f _{MCK}	—	ns
SCKp high-/low-level width	t _{Kh2} , t _{kl2}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V	t _{KCY2} /2 - 18	—	t _{KCY2} /2 - 50	—	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2	t _{KCY2} /2 - 50	—	t _{KCY2} /2 - 50	—	ns
Slp setup time (to SCKp↓) Note 3	t _{SIK2}	2.7 V ≤ V _{DD} ≤ 3.6 V	1/f _{MCK} + 20	—	1/f _{MCK} + 30	—	ns
		1.8 V ≤ V _{DD} < 3.3 V	1/f _{MCK} + 30	—	1/f _{MCK} + 30	—	ns
Slp hold time (from SCKp↑) Note 4	t _{ksi2}	—	1/f _{MCK} + 31	—	1/f _{MCK} + 31	—	ns
Delay time from SCKp↓ to SOp output Note 5	t _{ks02}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b ≤ 2.7 V C _b = 30 pF, R _b = 2.7 kΩ	—	2/f _{MCK} + 214	—	2/f _{MCK} + 573	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2 C _b = 30 pF, R _b = 5.5 kΩ	—	2/f _{MCK} + 573	—	2/f _{MCK} + 573	ns

Note 1. Transfer rate in the SNOOZE mode: MAX. 1 Mbps**Note 2.** Use it with V_{DD} ≥ V_b.**Note 3.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp setup time becomes "to SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.**Note 4.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The Slp hold time becomes "from SCKp↓" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.**Note 5.** When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1. The delay time to SOp output becomes "from SCKp↑" when DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.**Caution** Select the TTL input buffer for the Slp pin and SCKp pin and the N-ch open drain output (V_{DD} tolerance) mode for the SOp pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

CSI mode connection diagram (during communication at different potential)

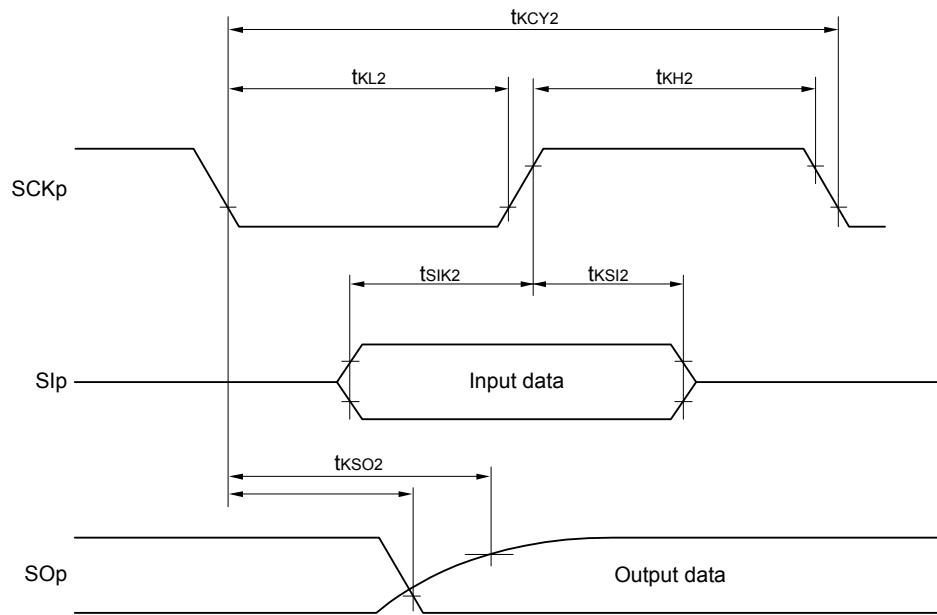
Remark 1. $R_b[\Omega]$: Communication line (SO_p) pull-up resistance, $C_b[F]$: Communication line (SO_p) load capacitance,
 $V_b[V]$: Communication line voltage

Remark 2. p: CSI number (p = 00, 10, 20, 30), m: Unit number (m = 0, 1), n: Channel number (n = 0 to 3),
g: PIM and POM number (g = 0, 1, 3, 4, 8)

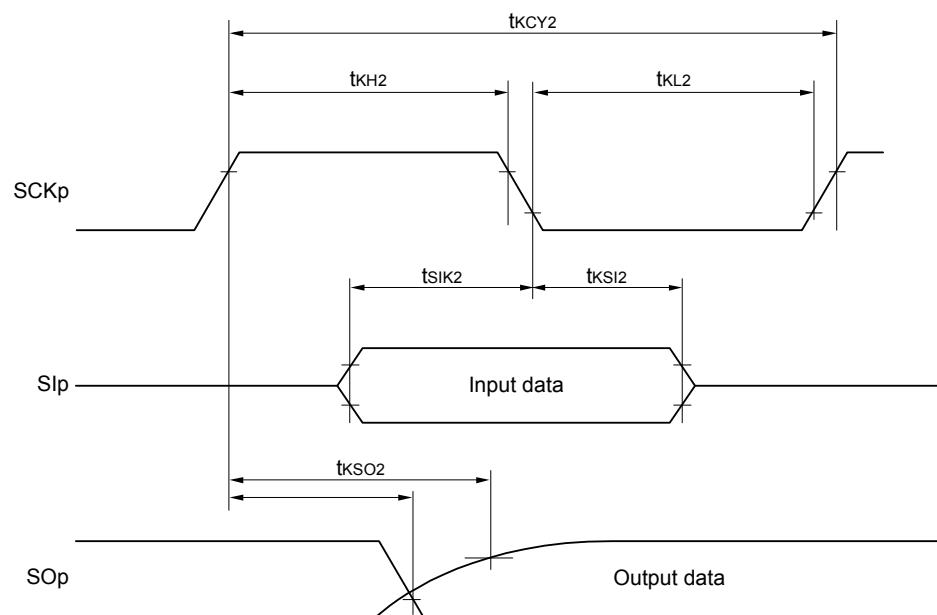
Remark 3. fmck: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number,
n: Channel number (mn = 00, 02, 10, 12))

CSI mode serial transfer timing (slave mode) (during communication at different potential)
 (When DAPmn = 0 and CKPmn = 0, or DAPmn = 1 and CKPmn = 1.)



CSI mode serial transfer timing (slave mode) (during communication at different potential)
 (When DAPmn = 0 and CKPmn = 1, or DAPmn = 1 and CKPmn = 0.)



Remark p: CSI number (p = 00, 10, 20, 30), m: Unit number (m = 0, 1),
 n: Channel number (n = 0 to 3), g: PIM and POM number (g = 0, 1, 3, 4, 8)

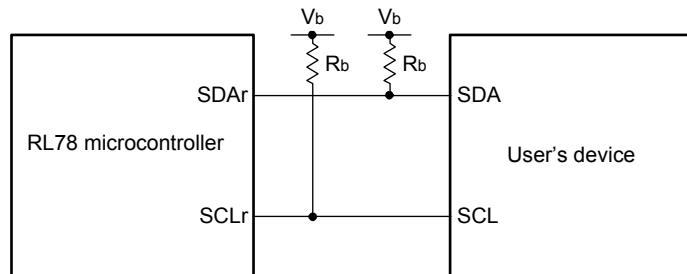
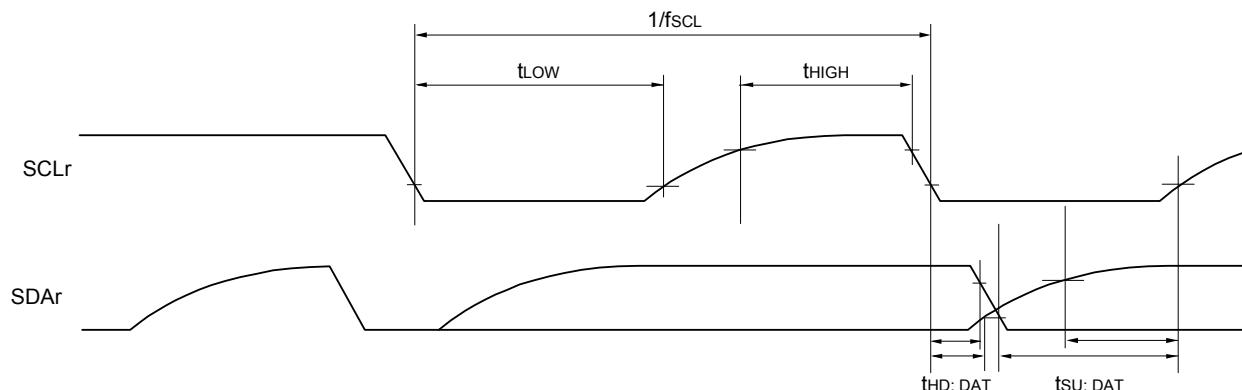
(10) Communication at different potential (1.8 V, 2.5 V) (simplified I²C mode)(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
			MIN.	MAX.	MIN.	MAX.	
SCL _r clock frequency	f _{SCL}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ		1000 Note 1		300 Note 1	kHz
		2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ		400 Note 1		300 Note 1	kHz
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2, C _b = 100 pF, R _b = 5.5 kΩ		400 Note 1		300 Note 1	kHz
Hold time when SCL _r = "L"	t _{LOW}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	475		1550		ns
		2.7 V ≤ V _{DD} < 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	1150		1550		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2, C _b = 100 pF, R _b = 5.5 kΩ	1550		1550		ns
Hold time when SCL _r = "H"	t _{HIGH}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	200		610		ns
		2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	600		610		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2, C _b = 100 pF, R _b = 5.5 kΩ	610		610		ns
Data setup time (reception)	t _{SU:DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	1/f _{MCK} + 135 Note 3		1/f _{MCK} + 190 Note 3		ns
		2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	1/f _{MCK} + 190 Note 3		1/f _{MCK} + 190 Note 3		ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2, C _b = 100 pF, R _b = 5.5 kΩ	1/f _{MCK} + 190 Note 3		1/f _{MCK} + 190 Note 3		ns
Data hold time (transmission)	t _{HD:DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 50 pF, R _b = 2.7 kΩ	0	305	0	305	ns
		2.7 V ≤ V _{DD} ≤ 3.6 V, 2.3 V ≤ V _b < 2.7 V, C _b = 100 pF, R _b = 2.7 kΩ	0	355	0	355	ns
		1.8 V ≤ V _{DD} < 3.3 V, 1.6 V ≤ V _b ≤ 2.0 V Note 2, C _b = 100 pF, R _b = 5.5 kΩ	0	405	0	405	ns

Note 1. The value must also be equal to or less than f_{MCK}/4.**Note 2.** Use it with V_{DD} ≥ V_b.**Note 3.** Set the f_{MCK} value to keep the hold time of SCL_r = "L" and SCL_r = "H".

Caution Select the TTL input buffer and the N-ch open drain output (V_{DD} tolerance) mode for the SDAr pin and the N-ch open drain output (V_{DD} tolerance) mode for the SCL_r pin by using port input mode register g (PIMg) and port output mode register g (POMg). For V_{IH} and V_{IL}, see the DC characteristics with TTL input buffer selected.

(Remarks are listed on the next page.)

Simplified I²C mode connection diagram (during communication at different potential)**Simplified I²C mode serial transfer timing (during communication at different potential)**

Remark 1. $R_b[\Omega]$: Communication line (SDAr, SCLR) pull-up resistance, $C_b[F]$: Communication line (SDAr, SCLR) load capacitance, $V_b[V]$: Communication line voltage

Remark 2. r: IIC number ($r = 00, 10, 20, 30$), g: PIM, POM number ($g = 0, 1, 3, 4, 8$)

Remark 3. fmCK: Serial array unit operation clock frequency

(Operation clock to be set by the CKSmn bit of serial mode register mn (SMRmn). m: Unit number ($m = 0, 1$), n: Channel number ($n = 0, 2$), mn = 00, 02, 10, 12)

2.5.2 Serial interface IICA

(1) I²C standard mode

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	HS (high-speed main) Mode		LS (low-speed main) Mode		Unit	
			MIN.	MAX.	MIN.	MAX.		
SCLA0 clock frequency	f _{SCL}	Standard mode: f _{CLK} ≥ 1 MHz	2.7 V ≤ V _{DD} ≤ 3.6 V	0	100	0	100	kHz
			1.8 V ≤ V _{DD} ≤ 3.6 V	—	—	0	100	kHz
Setup time of restart condition	t _{SU: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.7	—	4.7	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.7	—	μs
Hold time Note 1	t _{HD: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.0	—	4.0	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.0	—	μs
Hold time when SCLA0 = "L"	t _{LOW}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.7	—	4.7	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.7	—	μs
Hold time when SCLA0 = "H"	t _{HIGH}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.0	—	4.0	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.0	—	μs
Data setup time (reception)	t _{SU: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V		250	—	250	—	ns
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	250	—	ns
Data hold time (transmission) Note 2	t _{HD: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V		0	3.45	0	3.45	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0	3.45	μs
Setup time of stop condition	t _{SU: STO}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.0	—	4.0	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.0	—	μs
Bus-free time	t _{BUF}	2.7 V ≤ V _{DD} ≤ 3.6 V		4.7	—	4.7	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	4.7	—	μs

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.

Note 2. The maximum value (MAX.) of t_{HD: DAT} is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.

Remark The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.

Standard mode: C_b = 400 pF, R_b = 2.7 kΩ

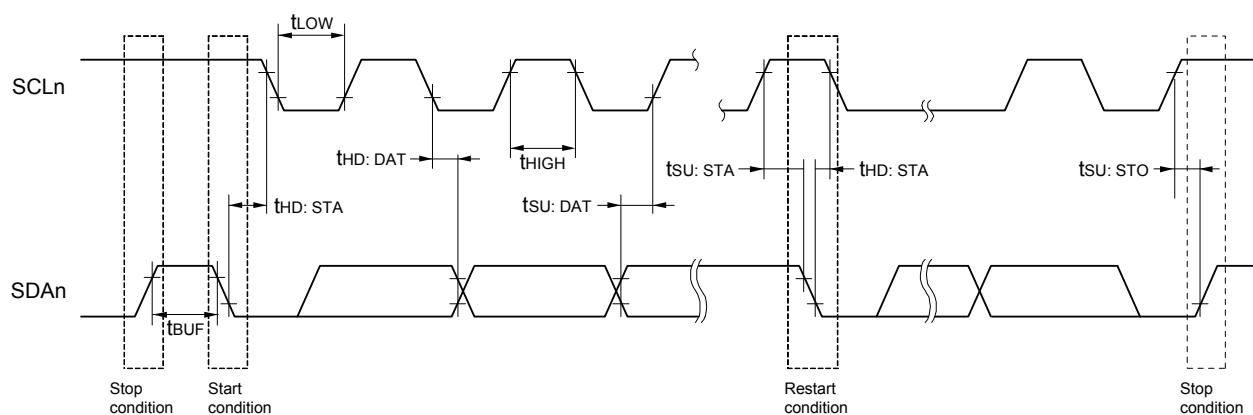
(2) I²C fast mode(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	f _{SCL}	Fast mode: f _{CLK} ≥ 3.5 MHz	2.7 V ≤ V _{DD} ≤ 3.6 V	0	400	0	400	kHz
			1.8 V ≤ V _{DD} ≤ 3.6 V	0	400	0	400	kHz
Setup time of restart condition	t _{SU: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V		0.6	—	0.6	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0.6	—	μs
Hold time Note 1	t _{HD: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V		0.6	—	0.6	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0.6	—	μs
Hold time when SCLA0 = "L"	t _{LOW}	2.7 V ≤ V _{DD} ≤ 3.6 V		1.3	—	1.3	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	1.3	—	μs
Hold time when SCLA0 = "H"	t _{HIGH}	2.7 V ≤ V _{DD} ≤ 3.6 V		0.6	—	0.6	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0.6	—	μs
Data setup time (reception)	t _{SU: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V		100	—	100	—	ns
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	100	—	ns
Data hold time (transmission) Note 2	t _{HD: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V		0	0.9	0	0.9	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0	0.9	μs
Setup time of stop condition	t _{SU: STO}	2.7 V ≤ V _{DD} ≤ 3.6 V		0.6	—	0.6	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	0.6	—	μs
Bus-free time	t _{BUF}	2.7 V ≤ V _{DD} ≤ 3.6 V		1.3	—	1.3	—	μs
		1.8 V ≤ V _{DD} ≤ 3.6 V		—	—	1.3	—	μs

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.**Note 2.** The maximum value (MAX.) of t_{HD: DAT} is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.**Remark** The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.Fast mode: C_b = 320 pF, R_b = 1.1 kΩ

(3) I²C fast mode plus(TA = -40 to +85 °C, 2.7 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		HS (high-speed main) Mode		LS (low-speed main) Mode		Unit
				MIN.	MAX.	MIN.	MAX.	
SCLA0 clock frequency	f _{SCL}	Fast mode plus: f _{CLOCK} ≥ 10 MHz	2.7 V ≤ V _{DD} ≤ 3.6 V	0	1000	—	—	kHz
Setup time of restart condition	t _{SU: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.26	—	—	—	μs
Hold time Note 1	t _{HD: STA}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.26	—	—	—	μs
Hold time when SCLA0 = "L"	t _{LOW}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.5	—	—	—	μs
Hold time when SCLA0 = "H"	t _{HIGH}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.26	—	—	—	μs
Data setup time (reception)	t _{SU: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	50	—	—	—	ns
Data hold time (transmission) Note 2	t _{HD: DAT}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0	0.45	—	—	μs
Setup time of stop condition	t _{SU: STO}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.26	—	—	—	μs
Bus-free time	t _{BUF}	2.7 V ≤ V _{DD} ≤ 3.6 V	—	0.5	—	—	—	μs

Note 1. The first clock pulse is generated after this period when the start/restart condition is detected.**Note 2.** The maximum value (MAX.) of t_{HD: DAT} is during normal transfer and a wait state is inserted in the ACK (acknowledge) timing.**Remark** The maximum value of C_b (communication line capacitance) and the value of R_b (communication line pull-up resistor) at that time in each mode are as follows.Fast mode plus: C_b = 120 pF, R_b = 1.1 kΩI²C serial transfer timing

2.6 Analog Characteristics

2.6.1 A/D converter characteristics

TA = -40 to +85°C, 1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = AVss = 0 V, reference voltage(+) = AVREFP, reference voltage(-) = AVREFM = 0 V

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit
Resolution	RES			—	—	12	bit
Analog capacitance	Cs			—	—	15	pF
Analog input resistance	Rs			—	—	2.5	kΩ
Frequency	f _{CLK}	High-speed mode	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	1	—	24	MHz
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	1	—	16	MHz
		Normal mode	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	1	—	24	MHz
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	1	—	16	MHz
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	1	—	8	MHz
Conversion time	Tconv	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 0.3 kΩ ADCLK = 24 MHz	3	—	—	μs
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 1.3 kΩ ADCLK = 16 MHz	4.5	—	—	μs
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 1.1 kΩ ADCLK = 24 MHz	3.4	—	—	μs
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 2.2 kΩ ADCLK = 16 MHz	5.1	—	—	μs
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 5 kΩ ADCLK = 8 MHz	10.1	—	—	μs
Overall error	AINL	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28 H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.25	±5.0	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.25	±5.0	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.25	±5.0	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.25	±5.0	LSB
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±3.0	±8.0	LSB
Zero-scale error	Ezs	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.5	±4.5	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.5	±4.5	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.5	±4.5	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.5	±4.5	LSB
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1	±7.5	LSB

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit
Full-scale error	EFS	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.75	±4.5	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.75	±4.5	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.75	±4.5	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±0.75	±4.5	LSB
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.5	±7.5	LSB
		Differential linearity error	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	—	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	—	LSB
			2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	—	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	—	LSB
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	—	LSB
			2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±3.0	LSB
Integral linearity error	ILE	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±4.5	LSB
			2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±3.0	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±3.0	LSB
			2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±3.0	LSB
			1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	±1.0	±3.0	LSB

Note The characteristics above only apply when pins other than those of the A/D converter are not in use. The overall error includes the quantization error. Each of the offset error, full-scale error, DNL differential non-linearity error, and INL integral non-linearity error does not include the quantization error.

[Reference value for design (not guaranteed)]

We can provide the design reference values for the A/D converter. Note, however, that these values are not guaranteed and can only be used as a reference when using this function. See below for details.

TA = 0 to +50°C, 2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = AVss = 0 V, reference voltage(+) = AVREFP, reference voltage(−) = AVREFM = 0 V

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit
Resolution	RES			—	—	—Note 3	bit
Analog capacitance	Cs			—	—	—Note 3	pF
Analog input resistance	Rs			—	—	—Note 3	kΩ
Frequency	fCLK	High-speed mode	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—Note 3	—	—Note 3	MHz
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—Note 3	—	—Note 3	MHz
		Normal mode	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—Note 3	—	—Note 3	MHz
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—Note 3	—	—Note 3	MHz
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—Note 3	—	—Note 3	MHz

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit
Conversion time	Tconv	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 0.3 kΩ ADCLK = 24 MHz	—Note 3	—	—	μs
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 1.3 kΩ ADCLK = 16 MHz	—Note 3	—	—	μs
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 1.1 kΩ ADCLK = 24 MHz	—Note 3	—	—	μs
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 2.2 kΩ ADCLK = 16 MHz	—Note 3	—	—	μs
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V Permissible signal source impedance max = 5 kΩ ADCLK = 8 MHz	—Note 3	—	—	μs
Overall error	AINL	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
Zero-scale error Note 1, Note 2	Ezs	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	±4.5	LSB
Full-scale error Note 1, Note 2	EFS	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	±4.5	LSB
Differential linearity error	DLE	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—	LSB
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—	LSB
Integral linearity error	ILE	High-speed mode ADCSR.ADHSC = 0 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
		Normal mode ADCSR.ADHSC = 1 ADSSTRn = 28H	2.7 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.4 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB
			2.0 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V	—	—Note 3	—Note 3	LSB

Note The characteristics above only apply when pins other than those of the A/D converter are not in use. The overall error includes the quantization error. Each of the offset error, full-scale error, DNL differential non-linearity error, and INL integral non-linearity error does not include the quantization error.

Note 1. MAX. value is the average value $\pm 3\sigma$ at normalized distribution.

Note 2. These values are the results of characteristic evaluation.

Note 3. The reference value is not available.

2.6.2 Temperature sensor, internal reference voltage output characteristics

(TA = -40 to +85 °C, 2.4 V ≤ VDD ≤ 3.6 V, Vss = 0 V), HS (high-speed main) mode

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Temperature sensor output voltage	VTMPS25	TA = +25°C		1.05		V
Internal reference voltage	VBRG		1.38	1.45	1.5	V
Temperature coefficient	FVTMPS	Temperature sensor output voltage that depends on the temperature		-3.6		mV/°C
Operation stabilization wait time	tAMP	2.4 V ≤ VDD ≤ 3.6 V	5			μs

2.6.3 D/A converter characteristics

(1) When reference voltage = AVREFP, AVREFM

(TA = -40 to +85 °C, 1.8 V ≤ AVREFP ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	R _E S				12	bit
Load resistance	R _O		30			kΩ
Load capacitance	C _O				50	pF
Output voltage range	T _{out}		0.35		AVDD - 0.47	V
Differential linearity error	DNL			±0.5	±1.0	LSB
Integral linearity error	A _I NL			±0.4	±8.0	LSB
Zero-scale error	E _Z S				±20	mV
Full-scale error	E _F S				±20	mV
Output resistance	R _O			5		Ω
Conversion time	t _{con}				30	μs

(2) When reference voltage = AVDD, AVss

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, Vss = AVss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Resolution	R _E S				12	bit
Load resistance	R _O		30			kΩ
Load capacitance	C _O				50	pF
Output voltage range	T _{out}		0.35		AVDD - 0.47	V
Differential linearity error	DNL			±0.5	±2.0	LSB
Integral linearity error	A _I NL			±0.4	±8.0	LSB
Zero-scale error	E _Z S				±30	mV
Full-scale error	E _F S				±30	mV
Output resistance	R _O			5		Ω
Conversion time	t _{con}				30	μs

2.6.4 Comparator

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Input voltage range	Ivref			0		V _{DD} - 1.4	V
	Ivcmp			-0.3		V _{DD} + 0.3	V
Output delay	td	V _{DD} = 3.0 V Input slew rate > 50 mV/μs	High-speed comparator mode, standard mode			1.2	μs
			High-speed comparator mode, window mode			2.0	μs
			Low-speed comparator mode, standard mode		3	5.0	μs
High-electric-potential judgment voltage	VTW+	High-speed comparator mode, window mode		0.76 V _{DD}			V
Low-electric-potential judgment voltage	VTW-	High-speed comparator mode, window mode		0.24 V _{DD}			V
Operation stabilization wait time	tcMP			100			μs
Internal reference voltage ^{Note}	VBGR			1.38	1.45	1.50	V

Note Not usable in LS (low-speed main) mode, sub-clock operation, or STOP mode.

2.6.5 Rail to rail Operational amplifier characteristics

(TA = -40 to +85 °C, 2.2 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit	
Circuit current	Icc1	Low-power consumption mode		—	10	16	µA	
	Icc2	High-speed mode		—	210	350	µA	
Common mode input range	Vicm1	Low-power consumption mode		0.1	—	AVDD-0.1	V	
	Vicm2	High-speed mode		0.1	—	AVDD-0.1	V	
Output voltage range	Vo1	Low-power consumption mode		0.1	—	AVDD-0.1	V	
	Vo2	High-speed mode		0.1	—	AVDD-0.1	V	
Input offset voltage	Fioff	Low-power consumption mode		-10	—	10	mV	
		High-speed mode		-5	—	5	mV	
Open gain	Av			—	120	—	dB	
Gain-bandwidth (GB) product	GBW1	Low-power consumption mode		—	0.06	—	MHz	
	GBW2	High-speed mode		—	1	—	MHz	
Phase margin	PM	CL = 22 pF		50	—	—	deg	
Gain margin	GM	CL = 20 pF		10	—	—	dB	
Equivalent input noise	Vnoise1	f = 1 kHz	Low-power consumption mode	—	900	—	nV/√Hz	
	Vnoise2	f = 10 kHz		—	450	—	nV/√Hz	
	Vnoise3	f = 1 kHz	High-speed mode	—	80	—	nV/√Hz	
	Vnoise4	f = 2 kHz		—	50	—	nV/√Hz	
Power supply reduction ratio	PSRR			—	90	—	dB	
Common mode signal reduction ratio	CMPR			—	90	—	dB	
Operation stabilization wait time	Tturn1	CL = 20 pF	Low-power consumption mode	—	110	300	µs	
	Tturn2	CL = 20 pF	High-speed mode	—	5	14	µs	
Settling time	Tset1	CL = 20 pF	Low-power consumption mode	—	100	300	µs	
	Tset2	CL = 20 pF	High-speed mode	—	4	14	µs	
Slew rate	Tselw1	CL = 20 pF	Low-power consumption mode	0.01	0.04	—	V/µs	
	Tselw2	CL = 20 pF	High-speed mode	0.3	0.7	—	V/µs	
Load current	Iload1	Low-power consumption mode		-110	—	110	µA	
	Iload2	High-speed mode		-110	—	110	µA	
Load capacitance	CL			—	—	22	pF	
Analog MUX ON resistance	Ron	One channel		—	—	1	kΩ	

[Reference value for design (not guaranteed)]

We can provide the design reference values for the rail-to-rail operational amplifier. Note, however, that these values are not guaranteed and can only be used as a reference when using this function. See below for details.

(TA = 0 to 50°C, 2.0 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Parameter	Symbol	Conditions		MIN	TYP	MAX	Unit	
Circuit current	Icc1	Low-power consumption mode		—	—Note 3	—Note 3	µA	
	Icc2	High-speed mode		—	—Note 3	—Note 3	µA	
Common mode input range	Vicm1	Low-power consumption mode		—Note 3	—	—Note 3	V	
	Vicm2	High-speed mode		—Note 3	—	—Note 3	V	
Output voltage range	Vo1	Low-power consumption mode		—Note 3	—	—Note 3	V	
	Vo2	High-speed mode		—Note 3	—	—Note 3	V	
Input offset voltage Note 1, Note 2	Fioff	Low-power consumption mode		-7	—	7	mV	
		High-speed mode		—Note 3	—	—Note 3	mV	
Open gain	Av			—Note 3	—Note 3	—	dB	
Gain-bandwidth (GB) product	GBW1	Low-power consumption mode		—	—Note 3	—	MHz	
	GBW2	High-speed mode		—	—Note 3	—	MHz	
Phase margin	PM	CL = 22 pF		—Note 3	—	—	deg	
Gain margin	GM	CL = 20 pF		—Note 3	—	—	dB	
Equivalent input noise	Vnoise1	f = 1 kHz	Low-power consumption mode	—	—Note 3	—	nV/√Hz	
	Vnoise2	f = 10 kHz		—	—Note 3	—	nV/√Hz	
	Vnoise3	f = 1 kHz	High-speed mode	—	—Note 3	—	nV/√Hz	
	Vnoise4	f = 2 kHz		—	—Note 3	—	nV/√Hz	
Power supply reduction ratio	PSRR			—	—Note 3	—	dB	
Common mode signal reduction ratio	CMPR			—	—Note 3	—	dB	
Operation stabilization wait time	Tstd1	CL = 20 pF	Low-power consumption mode	—	—Note 3	—Note 3	µs	
	Tstd2	CL = 20 pF	High-speed mode	—	—Note 3	—Note 3	µs	
Settling time	Tset1	CL = 20 pF	Low-power consumption mode	—	—Note 3	—Note 3	µs	
	Tset2	CL = 20 pF	High-speed mode	—	—Note 3	—Note 3	µs	
Slew rate	Tselw1	CL = 20 pF	Low-power consumption mode	—Note 3	—Note 3	—	V/µs	
	Tselw2	CL = 20 pF	High-speed mode	—Note 3	—Note 3	—	V/µs	
Load current	Iload1	Low-power consumption mode		—Note 3	—	—Note 3	µA	
	Iload2	High-speed mode		—Note 3	—	—Note 3	µA	
Load capacitance	CL			—	—	—Note 3	pF	
Analog MUX ON resistance	Ron	One channel		—	—	—Note 3	kΩ	

Note 1. MAX. value is the average value $\pm 3\sigma$ at normalized distribution.

Note 2. These values are the results of characteristic evaluation.

Note 3. The reference value is not available.

2.6.6 General purpose Operational amplifier characteristics

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit	
Circuit current	Icc1	Low-power consumption mode			2	4	µA	
	Icc2	High-speed mode			140	280	µA	
Common mode input range	Vicm1	Low-power consumption mode		0.2		AVDD-0.5	V	
	Vicm2	High-speed mode		0.3		AVDD-0.6	V	
Output voltage range	Vo1	Low-power consumption mode		0.1		AVDD-0.1	V	
	Vo2	High-speed mode		0.1		AVDD-0.1	V	
Input offset voltage	Fioff	3σ		-10		+10	mV	
Open gain	Av			60	120		dB	
Gain-bandwidth (GB) product	GBW1	Low-power consumption mode			0.04		MHz	
	GBW2	High-speed mode			1.7		MHz	
Phase margin	PM	CL = 20 pF		50			deg	
Gain margin	GM	CL = 20 pF		10			dB	
Equivalent input noise	Vnoise1	f = 1 kHz	Low-power con-sumption mode		230		nV/√Hz	
	Vnoise2	f = 10 kHz			200		nV/√Hz	
	Vnoise3	f = 1 kHz	High-speed mode		90		nV/√Hz	
	Vnoise4	f = 2 kHz			70		nV/√Hz	
Power supply reduction ratio	PSRP				90		dB	
Common mode signal reduction ratio	CMPR				90		dB	
Operation stabilization wait time	Tstd1	CL = 20 pF	Low-power con-sumption mode			650	µs	
	Tstd2	CL = 20 pF	High-speed mode			13	µs	
Settling time	Tset1	CL = 20 pF	Low-power con-sumption mode			750	µs	
	Tset2	CL = 20 pF	High-speed mode			13	µs	
Slew rate	Tselw1	CL = 20 pF	Low-power con-sumption mode		0.02		V/µs	
	Tselw2	CL = 20 pF	High-speed mode		1.1		V/µs	
Load current	Iload1	Low-power consumption mode		-100		100	µA	
	Iload2	High-speed mode		-100		100	µA	
Load capacitance	CL					20	pF	

2.6.7 Voltage reference

(TA = -40 to +85 °C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Reference voltage output	VREF1	VSEL = 00, 2.65 V ≤ AVDD ≤ 3.6V	2.425	2.5	2.575	V
	VREF2	VSEL = 01, 2.2 V ≤ AVDD ≤ 3.6V	1.987	2.048	2.109	V
	VREF3	VSEL = 10, 2.0 V ≤ AVDD ≤ 3.6V	1.746	1.8	1.854	V
	VREF4	VSEL = 11, 1.8 V ≤ AVDD ≤ 3.6V	1.455	1.5	1.545	V
Settling time		From power-on to AVDD set			50	ms
Load current of the VREFOUT pin	I _{Load}				200	µA

Note 1. Connect AVREFP/AVREFOUT pins to the ground via a tantalum capacitor (capacity: 10 µF ±30%, ESR: 2Ω (max.), ESL: 10 nH (max.)) and a ceramic capacitor (capacity: 0.1 µF ±30%, ESR: 2Ω (max.), ESL: 10nH (max.)).

Note 2. The values specified in the Reference voltage output column apply when a load is stable. These values cannot be guaranteed when the load is variable.

Note 3. Total load current, including the load current when VREFOUT is in use for the on-chip A/D converter and D/A converter reference potential.

When VREFOUT is in use for the on-chip A/D converter load reference, the maximum load current is 55 µA.

When VREFOUT is in use for the on-chip D/A converter (channel 1), the maximum load current is 55 µA.

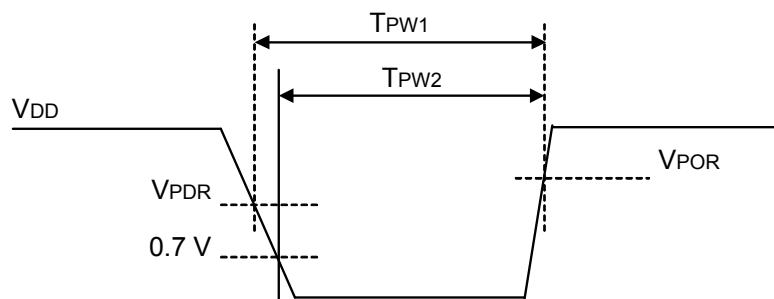
2.6.8 POR circuit characteristics

(TA = -40 to +85 °C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	V _{POR}	Power supply rise time	1.47	1.51	1.55	V
	V _{PDR}	Power supply fall time ^{Note 1}	1.46	1.50	1.54	V
Minimum pulse width Note 2	T _{PW1}	Other than STOP/SUB HALT/SUB RUN	300			μs
	T _{PW2}	STOP/SUB HALT/SUB RUN	300			μs

Note 1. If the power supply voltage falls while the voltage detector is off, be sure to either shift to STOP mode or execute a reset by using the voltage detector or external reset pin before the power supply voltage falls below the minimum operating voltage specified in 2.4 AC Characteristics.

Note 2. Minimum time required for a POR reset when V_{DD} exceeds below V_{PDR}. This is also the minimum time required for a POR reset from when V_{DD} exceeds below 0.7 V to when V_{DD} exceeds V_{POR} while STOP mode is entered or the main system clock is stopped through setting bit 0 (HIOSTOP) and bit 7 (MSTOP) in the clock operation status control register (CSC).



2.6.9 1/2 AV_{DD} voltage output

LVD Detection Voltage of Reset Mode and Interrupt Mode

(TA = -40 to +85 °C, 1.8 V ≤ AV_{DD} ≤ V_{DD} ≤ 3.6 V, AV_{SS} = V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Output voltage accuracy			-4.0		+4.0	%
Sampling time for the corresponding channel			20.0			μs

2.6.10 LVD circuit characteristics

**LVD Detection Voltage of Reset Mode and Interrupt Mode
(TA = -40 to +85 °C, VPDR ≤ VDD ≤ 3.6 V, Vss = 0 V)**

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Detection voltage	Supply voltage level	V _{LVD2}	Power supply rise time	3.07	3.13	3.19
			Power supply fall time	3.00	3.06	3.12
	V _{LVD3}		Power supply rise time	2.96	3.02	3.08
			Power supply fall time	2.90	2.96	3.02
	V _{LVD4}		Power supply rise time	2.86	2.92	2.97
			Power supply fall time	2.80	2.86	2.91
	V _{LVD5}		Power supply rise time	2.76	2.81	2.87
			Power supply fall time	2.70	2.75	2.81
	V _{LVD6}		Power supply rise time	2.66	2.71	2.76
			Power supply fall time	2.60	2.65	2.70
	V _{LVD7}		Power supply rise time	2.56	2.61	2.66
			Power supply fall time	2.50	2.55	2.60
	V _{LVD8}		Power supply rise time	2.45	2.50	2.55
			Power supply fall time	2.40	2.45	2.50
	V _{LVD9}		Power supply rise time	2.05	2.09	2.13
			Power supply fall time	2.00	2.04	2.08
	V _{LVD10}		Power supply rise time	1.94	1.98	2.02
			Power supply fall time	1.90	1.94	1.98
	V _{LVD11}		Power supply rise time	1.84	1.88	1.91
			Power supply fall time	1.80	1.84	1.87
Minimum pulse width	t _{LW}		300			μs
Detection delay time					300	μs

Caution Set the detection voltage (V_{LVD}) to be within the operating voltage range. The operating voltage range depends on the setting of the user option byte (000C2H/010C2H). The following shows the operating voltage range.

HS (high-speed main) mode: V_{DD} = 2.7 to 3.6 V @ 1 MHz to 24 MHz

V_{DD} = 2.4 to 3.6 V @ 1 MHz to 16 MHz

LS (low-speed main) mode: V_{DD} = 1.8 to 3.6 V @ 1 MHz to 8 MHz

LVD Detection Voltage of Interrupt & Reset Mode

(TA = -40 to +85 °C, VPDR ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
Interrupt and reset mode	VLVDB0	VPOCO, VPOC1, VPOC2 = 0, 0, 1, falling reset voltage: 1.8 V	Rising release reset voltage	1.80	1.84	1.87	V
	VLVDB1		Falling interrupt voltage	1.94	1.98	2.02	V
	VLVDB2	LVIS0, LVIS1 = 1, 0	Rising release reset voltage	1.90	1.94	1.98	V
	VLVDB3		Falling interrupt voltage	2.05	2.09	2.13	V
	VLVDC0	LVIS0, LVIS1 = 0, 1	Rising release reset voltage	2.00	2.04	2.08	V
	VLVDC1		Falling interrupt voltage	3.07	3.13	3.19	V
	VLVDC2	LVIS0, LVIS1 = 0, 0	Rising release reset voltage	3.00	3.06	3.12	V
	VLVDD0	VPOCO, VPOC1, VPOC2 = 0, 1, 0, falling reset voltage: 2.4 V	Rising release reset voltage	2.40	2.45	2.50	V
	VLVDD1		Falling interrupt voltage	2.56	2.61	2.66	V
	VLVDD2	LVIS0, LVIS1 = 1, 1	Rising release reset voltage	2.60	2.65	2.70	V
			Falling interrupt voltage	2.70	2.75	2.81	V
			Rising release reset voltage	2.86	2.92	2.97	V
			Falling interrupt voltage	2.80	2.86	2.91	V
			Rising release reset voltage	2.96	3.02	3.08	V
			Falling interrupt voltage	2.90	2.96	3.02	V

2.6.11 Low-resistance switch

TA = -40 to +85°C, 1.8 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V

Parameter	Symbol	Conditions	MIN	TYP	MAX	Unit
ON resistance 1	Ron1	AMP0OPD, AMP1OPD Load current < 0.1 mA	—	16	50	Ω
ON resistance 2	Ron2		—	10	30	
Load current	Icas	—	—	—	0.1	mA

[Reference value for design (not guaranteed)]

We can provide the design reference values for the low-resistance switch. Note, however, that these values are not guaranteed and can only be used as a reference when using this function. See below for details.

TA = 0 to +50°C, 2.0 V ≤ AVDD ≤ VDD ≤ 3.6 V, AVss = Vss = 0 V

Parameter	Symbol	Conditions	MIN	TYP	MAX	Unit
ON resistance 1 Note 1, Note 2	Ron1	AMP0OPD, AMP1OPD Load current < 0.1 mA	—	—Note 3	26	Ω
ON resistance 2 Note 1, Note 2	Ron2		—	—Note 3	15	
Load current	Icas	—	—	—	—Note 3	mA

Note 1. MAX. value is the average value $\pm 3\sigma$ at normalized distribution.**Note 2.** These values are the results of characteristic evaluation.**Note 3.** The reference value is not available.

2.7 Power supply voltage rising slope characteristics

(TA = -40 to +85 °C, Vss = 0 V)

Parameter	Conditions	MIN.	TYP.	MAX.	Unit
Power supply voltage rising slope	SVDD			54	V/ms

Caution Make sure to keep the internal reset state by the LVD circuit or an external reset until Vdd reaches the operating voltage range shown in 2.4 AC Characteristics.

2.8 LCD Characteristics

2.8.1 Resistance division method

(1) Static display mode

(TA = -40 to +85 °C, VL4 (MIN.) ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.0		VDD	V

(2) 1/2 bias method, 1/4 bias method

(TA = -40 to +85 °C, VL4 (MIN.) ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.7		VDD	V

(3) 1/3 bias method

(TA = -40 to +85 °C, VL4 (MIN.) ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD drive voltage	VL4		2.5		VDD	V

2.8.2 Internal voltage boosting method

(1) 1/3 bias method

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1	C1 to C4 Note 1 = 0.47 μF Note 2	VLCD = 04H	0.90	1.00	1.08	V
			VLCD = 05H	0.95	1.05	1.13	V
			VLCD = 06H	1.00	1.10	1.18	V
			VLCD = 07H	1.05	1.15	1.23	V
			VLCD = 08H	1.10	1.20	1.28	V
			VLCD = 09H	1.15	1.25	1.33	V
			VLCD = 0AH	1.20	1.30	1.38	V
			VLCD = 0BH	1.25	1.35	1.43	V
			VLCD = 0CH	1.30	1.40	1.48	V
			VLCD = 0DH	1.35	1.45	1.53	V
			VLCD = 0EH	1.40	1.50	1.58	V
			VLCD = 0FH	1.45	1.55	1.63	V
			VLCD = 10H	1.50	1.60	1.68	V
			VLCD = 11H	1.55	1.65	1.73	V
			VLCD = 12H	1.60	1.70	1.78	V
			VLCD = 13H	1.65	1.75	1.83	V
Doubler output voltage	VL2	C1 to C4 Note 1 = 0.47 μF	2 VL1 - 0.1	2 VL1	2 VL1	2 VL1	V
Tripler output voltage	VL4	C1 to C4 Note 1 = 0.47 μF	3 VL1 - 0.15	3 VL1	3 VL1	3 VL1	V
Reference voltage setup time Note 2	tVWAIT1		5				ms
Voltage boost wait time Note 3	tVWAIT2	C1 to C4 Note 1 = 0.47 μF	500				ms

Note 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between VL1 and GND

C3: A capacitor connected between VL2 and GND

C4: A capacitor connected between VL4 and GND

C1 = C2 = C3 = C4 = 0.47 μF±30%

Note 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).

Note 3. This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

(2) 1/4 bias method

(TA = -40 to +85 °C, 1.8 V ≤ V_{DD} ≤ 3.6 V, V_{SS} = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
LCD output voltage variation range	VL1	C1 to C5 Note 1 = 0.47 μF Note 2	VLCD = 04H	0.90	1.00	1.08
			VLCD = 05H	0.95	1.05	1.13
			VLCD = 06H	1.00	1.10	1.18
			VLCD = 07H	1.05	1.15	1.23
			VLCD = 08H	1.10	1.20	1.28
			VLCD = 09H	1.15	1.25	1.33
			VLCD = 0AH	1.20	1.30	1.38
Doubler output voltage	VL2	C1 to C5 Note 1 = 0.47 μF	2 VL1 - 0.08	2 VL1	2 VL1	V
Tripler output voltage	VL3	C1 to C5 Note 1 = 0.47 μF	3 VL1 - 0.12	3 VL1	3 VL1	V
Quadruply output voltage	VL4	C1 to C5 Note 1 = 0.47 μF	4 VL1 - 0.16	4 VL1	4 VL1	V
Reference voltage setup time Note 2	t _{VWAIT1}		5			ms
Voltage boost wait time Note 3	t _{VWAIT2}	C1 to C5 Note 1 = 0.47 μF	500			ms

Note 1. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between VL1 and GND

C3: A capacitor connected between VL2 and GND

C4: A capacitor connected between VL3 and GND

C5: A capacitor connected between VL4 and GND

C1 = C2 = C3 = C4 = C5 = 0.47 μF±30%

Note 2. This is the time required to wait from when the reference voltage is specified by using the VLCD register (or when the internal voltage boosting method is selected (by setting the MDSET1 and MDSET0 bits of the LCDM0 register to 01B) if the default value reference voltage is used) until voltage boosting starts (VLCON = 1).**Note 3.** This is the wait time from when voltage boosting is started (VLCON = 1) until display is enabled (LCDON = 1).

2.8.3 Capacitor split method

(1) 1/3 bias method

(TA = -40 to +85 °C, 2.2 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
V _{L4} voltage	V _{L4}	C1 to C4 = 0.47 µF Note 2		V _{DD}		V
V _{L2} voltage	V _{L2}	C1 to C4 = 0.47 µF Note 2	2/3 V _{L4} - 0.1	2/3 V _{L4}	2/3 V _{L4} + 0.1	V
V _{L1} voltage	V _{L1}	C1 to C4 = 0.47 µF Note 2	1/3 V _{L4} - 0.1	1/3 V _{L4}	1/3 V _{L4} + 0.1	V
Capacitor split wait time Note 1	t _{WAIT}		100			ms

Note 1. This is the wait time from when voltage bucking is started (VLCON = 1) until display is enabled (LCDON = 1).

Note 2. This is a capacitor that is connected between voltage pins used to drive the LCD.

C1: A capacitor connected between CAPH and CAPL

C2: A capacitor connected between VL1 and GND

C3: A capacitor connected between VL2 and GND

C4: A capacitor connected between VL4 and GND

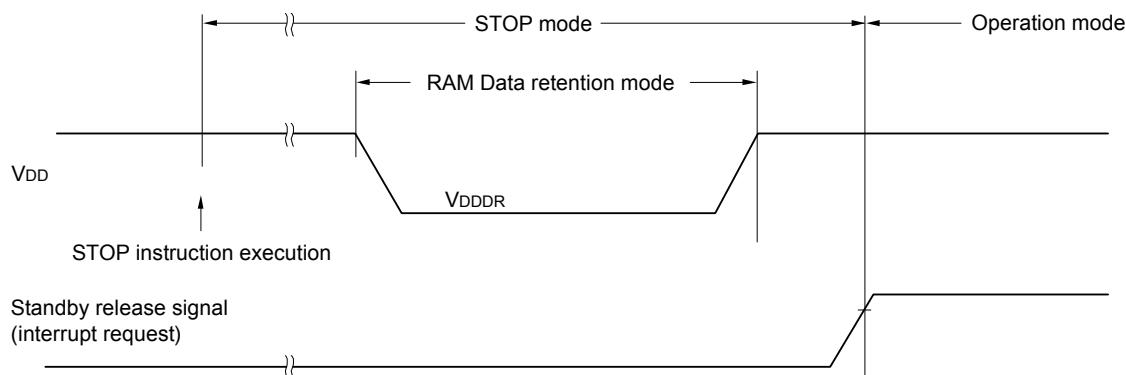
C1 = C2 = C3 = C4 = 0.47 µF±30%

2.9 RAM data retention characteristics

(TA = -40 to +85 °C, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Data retention supply voltage	VDDDR		1.46 Note		3.6	V

Note The value depends on the POR detection voltage. When the voltage drops, the RAM data is retained before a POR reset is effected, but RAM data is not retained when a POR reset is effected.



2.10 Flash Memory Programming Characteristics

(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions		MIN.	TYP.	MAX.	Unit
System clock frequency	fCLK	2.4 V ≤ VDD ≤ 3.6 V		1		24	MHz
Number of code flash rewrites Notes 1, 2, 3	Cerwr	Retained for 20 years	TA = 85°C	1,000			Times
Number of data flash rewrites Notes 1, 2, 3		Retained for 1 year	TA = 25°C		1,000,000		
		Retained for 5 years	TA = 85°C	100,000			
		Retained for 20 years	TA = 85°C	10,000			

Note 1. 1 erase + 1 write after the erase is regarded as 1 rewrite. The retaining years are until next rewrite after the rewrite.

Note 2. When using flash memory programmer and Renesas Electronics self programming library

Note 3. These are the characteristics of the flash memory and the results obtained from reliability testing by Renesas Electronics Corporation.

2.11 Dedicated Flash Memory Programmer Communication (UART)

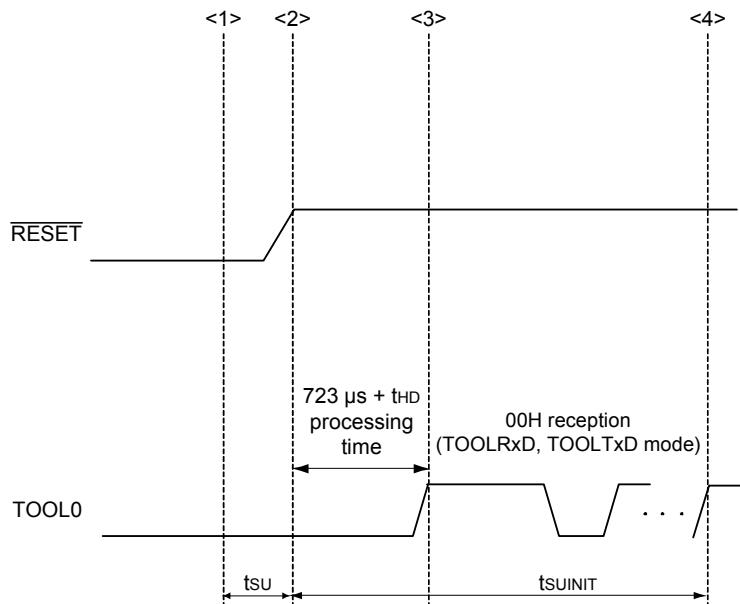
(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
Transfer rate		During serial programming	115,200		1,000,000	bps

2.12 Timing Specs for Switching Modes

(TA = -40 to +85 °C, 1.8 V ≤ VDD ≤ 3.6 V, Vss = 0 V)

Parameter	Symbol	Conditions	MIN.	TYP.	MAX.	Unit
How long from when an external reset ends until the initial communication settings are specified	tsINIT	POR and LVD reset must end before the external reset ends.			100	ms
How long from when the TOOL0 pin is placed at the low level until an external reset ends	tsU	POR and LVD reset must end before the external reset ends.	10			μs
Time to hold the TOOL0 pin at the low level after an external reset is released (excluding the processing time of the firmware to control the flash memory)	tHD	POR and LVD reset must end before the external reset ends.	1			ms



<1> The low level is input to the TOOL0 pin.

<2> The external reset ends (POR and LVD reset must end before the external reset ends.).

<3> The TOOL0 pin is set to the high level.

<4> Setting of the flash memory programming mode by UART reception and complete the baud rate setting.

Remark tsINIT: The segment shows that it is necessary to finish specifying the initial communication settings within 100 ms from when the resets end.

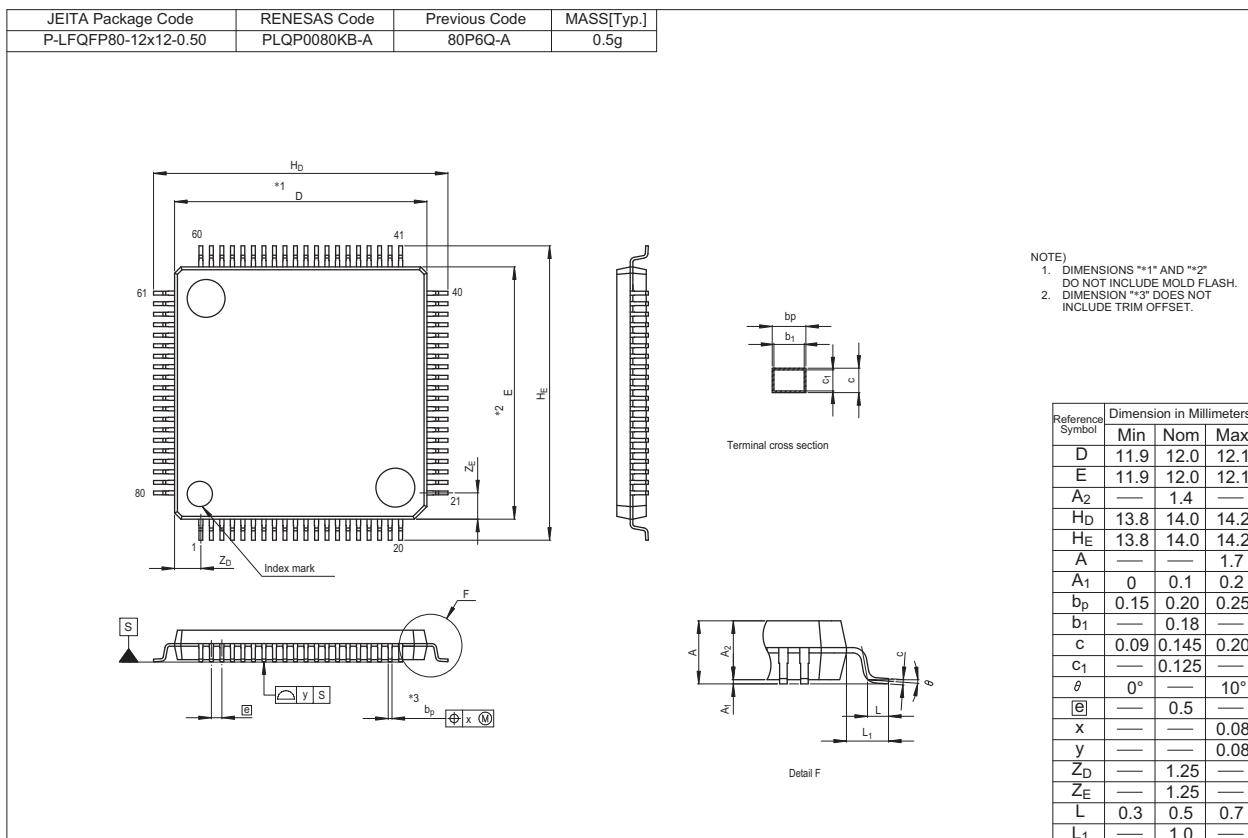
tsU: How long from when the TOOL0 pin is placed at the low level until an external reset ends

tHD: Time to hold the TOOL0 pin at the low level after an external reset is released (excluding the processing time of the firmware to control the flash memory)

3. PACKAGE DRAWINGS

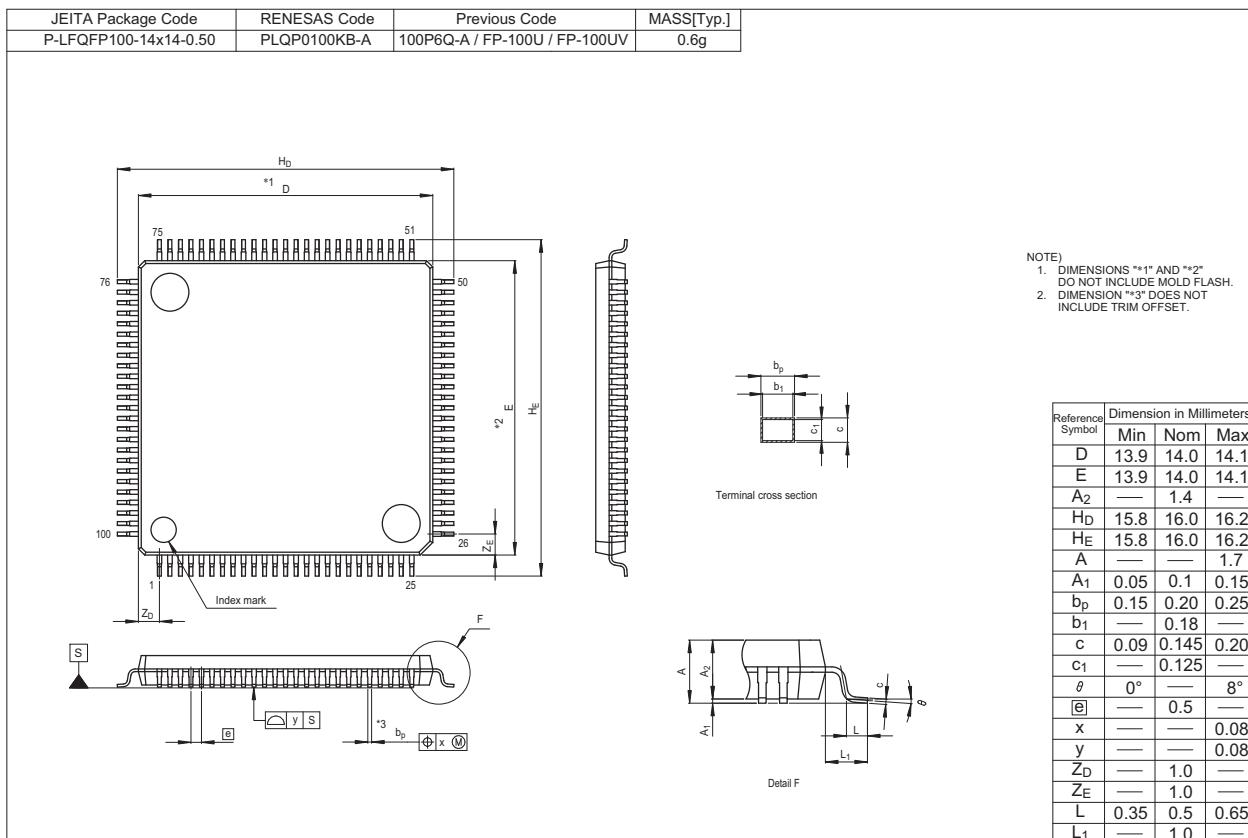
3.1 80-pin products

R5F11MMDAFB, R5F11MMEAFB, R5F11MMFAFB



3.2 100-pin products

R5F11MPEAFB, R5F11MPFAFB, R5F11MPGAFB



REVISION HISTORY		RL78/L1A Datasheet	
------------------	--	--------------------	--

Rev.	Date	Description	
		Page	Summary
1.00	Aug 12, 2016	—	First Edition issued

SuperFlash is a registered trademark of Silicon Storage Technology, Inc. in several countries including the United States and Japan.

Caution: This product uses SuperFlash® technology licensed from Silicon Storage Technology, Inc.

All trademarks and registered trademarks are the property of their respective owners.

NOTES FOR CMOS DEVICES

- (1) VOLTAGE APPLICATION WAVEFORM AT INPUT PIN: Waveform distortion due to input noise or a reflected wave may cause malfunction. If the input of the CMOS device stays in the area between VIL (MAX) and VIH (MIN) due to noise, etc., the device may malfunction. Take care to prevent chattering noise from entering the device when the input level is fixed, and also in the transition period when the input level passes through the area between VIL (MAX) and VIH (MIN).
- (2) HANDLING OF UNUSED INPUT PINS: Unconnected CMOS device inputs can be cause of malfunction. If an input pin is unconnected, it is possible that an internal input level may be generated due to noise, etc., causing malfunction. CMOS devices behave differently than Bipolar or NMOS devices. Input levels of CMOS devices must be fixed high or low by using pull-up or pull-down circuitry. Each unused pin should be connected to VDD or GND via a resistor if there is a possibility that it will be an output pin. All handling related to unused pins must be judged separately for each device and according to related specifications governing the device.
- (3) PRECAUTION AGAINST ESD: A strong electric field, when exposed to a MOS device, can cause destruction of the gate oxide and ultimately degrade the device operation. Steps must be taken to stop generation of static electricity as much as possible, and quickly dissipate it when it has occurred. Environmental control must be adequate. When it is dry, a humidifier should be used. It is recommended to avoid using insulators that easily build up static electricity. Semiconductor devices must be stored and transported in an anti-static container, static shielding bag or conductive material. All test and measurement tools including work benches and floors should be grounded. The operator should be grounded using a wrist strap. Semiconductor devices must not be touched with bare hands. Similar precautions need to be taken for PW boards with mounted semiconductor devices.
- (4) STATUS BEFORE INITIALIZATION: Power-on does not necessarily define the initial status of a MOS device. Immediately after the power source is turned ON, devices with reset functions have not yet been initialized. Hence, power-on does not guarantee output pin levels, I/O settings or contents of registers. A device is not initialized until the reset signal is received. A reset operation must be executed immediately after power-on for devices with reset functions.
- (5) POWER ON/OFF SEQUENCE: In the case of a device that uses different power supplies for the internal operation and external interface, as a rule, switch on the external power supply after switching on the internal power supply. When switching the power supply off, as a rule, switch off the external power supply and then the internal power supply. Use of the reverse power on/off sequences may result in the application of an overvoltage to the internal elements of the device, causing malfunction and degradation of internal elements due to the passage of an abnormal current. The correct power on/off sequence must be judged separately for each device and according to related specifications governing the device.
- (6) INPUT OF SIGNAL DURING POWER OFF STATE : Do not input signals or an I/O pull-up power supply while the device is not powered. The current injection that results from input of such a signal or I/O pull-up power supply may cause malfunction and the abnormal current that passes in the device at this time may cause degradation of internal elements. Input of signals during the power off state must be judged separately for each device and according to related specifications governing the device.

Notice

1. Descriptions of circuits, software and other related information in this document are provided only to illustrate the operation of semiconductor products and application examples. You are fully responsible for the incorporation of these circuits, software, and information in the design of your equipment. Renesas Electronics assumes no responsibility for any losses incurred by you or third parties arising from the use of these circuits, software, or information.
2. Renesas Electronics has used reasonable care in preparing the information included in this document, but Renesas Electronics does not warrant that such information is error free. Renesas Electronics assumes no liability whatsoever for any damages incurred by you resulting from errors in or omissions from the information included herein.
3. Renesas Electronics does not assume any liability for infringement of patents, copyrights, or other intellectual property rights of third parties by or arising from the use of Renesas Electronics products or technical information described in this document. No license, express, implied or otherwise, is granted hereby under any patents, copyrights or other intellectual property rights of Renesas Electronics or others.
4. You should not alter, modify, copy, or otherwise misappropriate any Renesas Electronics product, whether in whole or in part. Renesas Electronics assumes no responsibility for any losses incurred by you or third parties arising from such alteration, modification, copy or otherwise misappropriation of Renesas Electronics product.
5. Renesas Electronics products are classified according to the following two quality grades: "Standard" and "High Quality". The recommended applications for each Renesas Electronics product depends on the product's quality grade, as indicated below.
"Standard": Computers; office equipment; communications equipment; test and measurement equipment; audio and visual equipment; home electronic appliances; machine tools; personal electronic equipment; and industrial robots etc.
"High Quality": Transportation equipment (automobiles, trains, ships, etc.); traffic control systems; anti-disaster systems; anti-crime systems; and safety equipment etc.
Renesas Electronics products are neither intended nor authorized for use in products or systems that may pose a direct threat to human life or bodily injury (artificial life support devices or systems, surgical implants etc.), or may cause serious property damages (nuclear reactor control systems, military equipment etc.). You must check the quality grade of each Renesas Electronics product before using it in a particular application. You may not use any Renesas Electronics product for any application for which it is not intended. Renesas Electronics shall not be in any way liable for any damages or losses incurred by you or third parties arising from the use of any Renesas Electronics product for which the product is not intended by Renesas Electronics.
6. You should use the Renesas Electronics products described in this document within the range specified by Renesas Electronics, especially with respect to the maximum rating, operating supply voltage range, movement power voltage range, heat radiation characteristics, installation and other product characteristics. Renesas Electronics shall have no liability for malfunctions or damages arising out of the use of Renesas Electronics products beyond such specified ranges.
7. Although Renesas Electronics endeavors to improve the quality and reliability of its products, semiconductor products have specific characteristics such as the occurrence of failure at a certain rate and malfunctions under certain use conditions. Further, Renesas Electronics products are not subject to radiation resistance design. Please be sure to implement safety measures to guard them against the possibility of physical injury, and injury or damage caused by fire in the event of the failure of a Renesas Electronics product, such as safety design for hardware and software including but not limited to redundancy, fire control and malfunction prevention, appropriate treatment for aging degradation or any other appropriate measures. Because the evaluation of microcomputer software alone is very difficult, please evaluate the safety of the final products or systems manufactured by you.
8. Please contact a Renesas Electronics sales office for details as to environmental matters such as the environmental compatibility of each Renesas Electronics product. Please use Renesas Electronics products in compliance with all applicable laws and regulations that regulate the inclusion or use of controlled substances, including without limitation, the EU RoHS Directive. Renesas Electronics assumes no liability for damages or losses occurring as a result of your noncompliance with applicable laws and regulations.
9. Renesas Electronics products and technology may not be used for or incorporated into any products or systems whose manufacture, use, or sale is prohibited under any applicable domestic or foreign laws or regulations. You should not use Renesas Electronics products or technology described in this document for any purpose relating to military applications or use by the military, including but not limited to the development of weapons of mass destruction. When exporting the Renesas Electronics products or technology described in this document, you should comply with the applicable export control laws and regulations and follow the procedures required by such laws and regulations.
10. It is the responsibility of the buyer or distributor of Renesas Electronics products, who distributes, disposes of, or otherwise places the product with a third party, to notify such third party in advance of the contents and conditions set forth in this document, Renesas Electronics assumes no responsibility for any losses incurred by you or third parties as a result of unauthorized use of Renesas Electronics products.
11. This document may not be reproduced or duplicated in any form, in whole or in part, without prior written consent of Renesas Electronics.
12. Please contact a Renesas Electronics sales office if you have any questions regarding the information contained in this document or Renesas Electronics products, or if you have any other inquiries.

(Note 1) "Renesas Electronics" as used in this document means Renesas Electronics Corporation and also includes its majority-owned subsidiaries.

(Note 2) "Renesas Electronics product(s)" means any product developed or manufactured by or for Renesas Electronics.



SALES OFFICES

Renesas Electronics Corporation

<http://www.renesas.com>

Refer to "<http://www.renesas.com/>" for the latest and detailed information.

California Eastern Laboratories, Inc.

4590 Patrick Henry Drive, Santa Clara, California 95054-1817, U.S.A.
Tel: +1-408-919-2500, Fax: +1-408-988-0279

Renesas Electronics Europe Limited

Dukes Meadow, Millboard Road, Bourne End, Buckinghamshire, SL8 5FH, U.K
Tel: +44-1628-585-100, Fax: +44-1628-585-900

Renesas Electronics Europe GmbH

Arcadiastrasse 10, 40472 Düsseldorf, Germany
Tel: +49-211-6503-0, Fax: +49-211-6503-1327

Renesas Electronics (China) Co., Ltd.

Room 1709, Quantum Plaza, No.27 ZhiChunLu Haidian District, Beijing 100191, P.R.China
Tel: +86-10-8235-1155, Fax: +86-10-8235-7679

Renesas Electronics (Shanghai) Co., Ltd.

Unit 301, Tower A, Central Towers, 555 Langao Road, Putuo District, Shanghai, P. R. China 200333
Tel: +86-21-2226-0888, Fax: +86-21-2226-0999

Renesas Electronics Hong Kong Limited

Unit 1601-1611, 16/F., Tower 2, Grand Century Place, 193 Prince Edward Road West, Mongkok, Kowloon, Hong Kong
Tel: +852-2265-6688, Fax: +852 2886-9022

Renesas Electronics Taiwan Co., Ltd.

13F, No. 363, Fu Shing North Road, Taipei 10543, Taiwan
Tel: +886-2-8175-9600, Fax: +886 2-8175-9670

Renesas Electronics Singapore Pte. Ltd.

80 Bendemeer Road, Unit #06-02 Hyflux Innovation Centre, Singapore 339949
Tel: +65-6213-0200, Fax: +65-6213-0300

Renesas Electronics Malaysia Sdn.Bhd.

Unit 1207, Block B, Menara Amcorp, Amcorp Trade Centre, No. 18, Jln Persiaran Barat, 46050 Petaling Jaya, Selangor Darul Ehsan, Malaysia
Tel: +60-3-7955-9390, Fax: +60-3-7955-9510

Renesas Electronics India Pvt. Ltd.

No.777C, 100 Feet Road, HAL II Stage, Indiranagar, Bangalore, India
Tel: +91-80-67208700, Fax: +91-80-67208777

Renesas Electronics Korea Co., Ltd.

12F., 234 Teheran-ro, Gangnam-Gu, Seoul, 135-080, Korea
Tel: +82-2-558-3737, Fax: +82-2-558-5141

X-ON Electronics

Largest Supplier of Electrical and Electronic Components

Click to view similar products for 16-bit Microcontrollers - MCU category:

Click to view products by Renesas manufacturer:

Other Similar products are found below :

[M30302FCFP#U3](#) [MB90F036APMC-GSE1](#) [MB90F428GCPFR-GSE1](#) [MB96F683RBPMC-GSAE1](#) [R5F10MMGDFB#30](#)
[R5F111PGGFB#30](#) [R5F117BCGNA#20](#) [DF3026XBL25V](#) [DF36014GFTV](#) [DF36014GFXV](#) [DF36034GFPV](#) [R5F11B7EANA#U0](#)
[R5F21172DSP#U0](#) [MB90092PF-G-BNDE1](#) [MB90F335APMC1-G-SPE1](#) [MB90F345CAPFR-GSE1](#) [MB90F568PMCR-GE1](#)
[MB96F395RSAPMC-GSE2](#) [DF36024GFXV](#) [UPD78F1018F1-BA4-A](#) [MB96F018RBPMC-GSE1](#) [MB90F867ASPFR-GE1](#)
[M30290FCHP#U3A](#) [DF2239FA20IV](#) [R5F117BCGFP#30](#) [LC88F58B0AU-SQFPH](#) [MB90F548GPF-GE1](#) [MB90214PF-GT-310-BND-AE1](#)
[MB90F342CESPQC-GSE2](#) [MB90F428GAPF-GSE1](#) [ML620Q504H-NNNTBWBX](#) [S912ZVH128F2VLL](#) [UPD78F1500AGK-GAK-AX](#)
[HD64F3337SF16V](#) [MB90F428GCPF-GSE1](#) [MB90F342ESPMC-G-JNE1](#) [MB90022PF-GS-358E1](#) [MB96F395RWAPMC-GSE2](#)
[MB96395RSAPMC-GS-110E2](#) [MB90F883CSPMC-GE1](#) [S912ZVHY64F1CLL](#) [S912ZVHY64F1VLQ](#) [ST10F280](#) [MB96F338RSAPMCR-GK5E2](#) [CY90096PF-G-002-BND-ERE1](#) [ML62Q1569-NNNGAZ0AX](#) [ML62Q1739-NNNGAZ0AX](#) [ML62Q1749-NNNGAZ0AX](#)
[ML62Q1579-NNNGAZ0AX](#) [ML62Q1559-NNNGAZ0AX](#)